TEST REPORT

Applicant :	M5Stack Technology Co., Ltd
Address :	Block A10, Expo Bay South Coast, Fuhai Street, Bao'an District, Shenzhen, China
Report Number :	2504X39110E-RF-07A

Test Standard (s)

Japan item 19 of Article 2 Paragraph 1

Sample Description

Product Type:	M5NanoH2
Model No.:	NanoH2
Trade Mark:	M5STACK
Date Received:	2025-09-29
Report Date:	2025-10-22

Test Result:	The EUT complied with the standards above.

Prepared and Checked By:

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Amanda Wei
EMC Engineer

Approved By:

Bob.Liao

Bob.Liao
EMC Engineer

Note: The information marked "#" is provided by the applicant, the laboratory is not responsible for its authenticity and this information can affect the validity of the result in the test report. Customer model name, addresses, names, trademarks etc. are included but no need marked.
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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Revision
Rev.00	2504X39110E-RF-07A	Original Report	2025-10-22

複製禁止

GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

Product		M5NanoH2
Tested Model		NanoH2
Radio Type		BLE (1M& 2M)
Technical Parameters	Modulation Type	GFSK
	Frequency Range	2402-2480MHz
	Output Power#	BLE 1M:3mW BLE 2M:2mW
	Antenna Gain#	-6.11dBi (provided by the applicant)
Nominal Power Supply#		DC 5V from Type-C port
Sample Serial Number		3AWK-2 (Assigned by ATC, Shenzhen)
Sample/EUT Status		Good condition

Objective

The objective of this current document is to demonstrate the EUT, as equipment type in Certification Ordinance Article 2-1-19 of Specific Radio Equipment Specified in Article 38-2-2 Paragraph 1 Item 1of the Radio Low, compliant with Article 49-20 of Radio equipment regulations.

Test Methodology

All measurements contained in this report were conducted with technical regulations of MIC Notice No.88 of 2004, Appendix No.43 (Version: MIC Notice No.409 of 2023).

Unless otherwise stated there are no any additions to, deviations, or exclusions from the method.

Test Facility

The test site used by Shenzhen Accurate Technology Co., Ltd. to collect test data is located on the Floor 1, KuMaKe Building, Dongzhou Community, Guangming Street, Guangming District, Shenzhen, Guangdong, China.

Measurement Uncertainty

Parameter	Uncertainty
Occupied Channel Bandwidth	5 %
RF Frequency	$0.064*10^{-7}$
RF output power, conducted	0.3 dB
Unwanted Emission, conducted	1.2 dB
Temperature	1 ℃
Humidity	7 %
Supply voltages	0.4 %

Note: The extended uncertainty given in this report is obtained by combining the standard uncertainty times the coverage factor K with the 95% confidence interval. Otherwise required by the applicant or Product Regulations, Decision Rule in this report did not consider the uncertainty.

EUT TEST CONFIGURATION

Description of Test Configuration

The system was configured for testing in engineering mode.

40 channels are provided for testing:

Channel	Frequency (MHz)	Channel	Frequency (MHz)
0	2402	20	2442
1	2404	21	2444
…	…	…	…
…	…	…	…
…	…	…	…
18	2438	38	2478
19	2440	39	2480

EUT was tested with channel 0, 19 and 39.

Test Voltage#

The EUT has no regulator chip, so the extremely high and low supply voltage condition shall be tested. (It is provided by the applicant.)

Test Condition	Input(V_{DC})
TC1(Normal Voltage)	5.0
TC2(Low Voltage)	4.5
TC3(High Voltage)	5.5

EUT Exercise Software and Power Level

"EspRFTestTool_v4.7_Manual" exercise software was made to the EUT tested and the power level was 14.

Equipment Modifications

No modification was made to the EUT tested.

Support Equipment List and Details

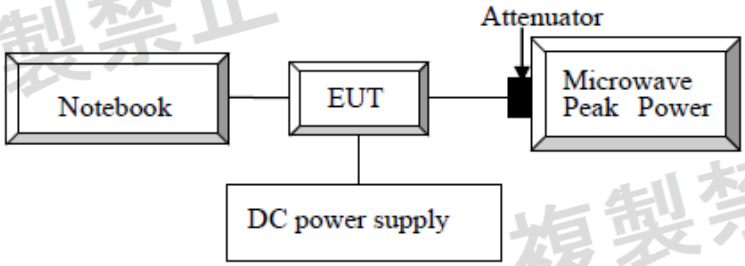
Manufacturer	Description	Model	Serial Number
LENOVO	Notebook	ThinkPad T470	PF-17P19A

External I/O Cable

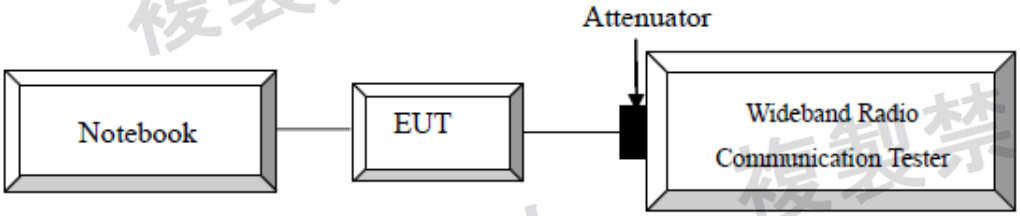
Cable Description	Length (m)	From Port	To
Un-shielding Detachable USB cable	0.8	EUT	Notebook
Un-shielding Detachable DC power cable	1.2	EUT	DC power supply
Un-shielding Detachable RF cable	0.05	EUT	Test Equipment

Configuration of Test Setup

For Antenna Output Power and Output Power Tolerance:

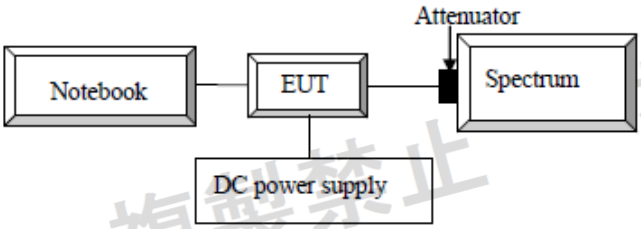


For Interference Prevention Function:



Note: Notebook to view the identification code through the "EspRFTestTool" software.

Other test items:



SUMMARY OF TEST RESULTS

MIC Notice No.88 of 2004, Appendix No.43, Article 2, Paragraph 1, Item 19

Items	Description of Test	Result
1	Frequency Tolerance	Compliance
2	Occupied Bandwidth	Compliance
3	Transmitter Spurious Emission and Unwanted Emission Intensity	Compliance
4	Antenna Output Power and Output Power Tolerance	Compliance
5	Receiver Spurious Emission and Unwanted Emission Intensity	Compliance
6	Carrier Sense Capability	Not Applicable**
7	Transmission Antenna Gain	Not Applicable
8	Transmission Radiation Angle Width	Not Applicable
9	Interference Prevention Function	Compliance
10	Frequency Hopping Dwell Time	Not Applicable*
11	Construction Protection Confirmation	Compliance

Not Applicable - This test item was not required for the output power less than 12.14 dBm (E.I.R.P).

Not Applicable* -Testing is only required for FHSS system devices.

Not Applicable**-The OBW of EUT is less than 26 MHz and the EUT is not radio control model aircraft.

Note: The cable loss is 0.5 dB$^{\#}$ and the attenuator is 10 dB, which was added into all test results.

TEST EQUIPMENT LIST

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Authority	Calibration Method
Anritsu	Microwave Peak Power Sensor	MA24418A	12619	2025/03/26	2026/03/25	BACL Cal	C
Rohde & Schwarz	Spectrum Analyzer	FSV-40	101948	2025/09/18	2026/09/17	BACL Cal	C
Rohde & Schwarz	Wideband Radio Communication Tester	CMW500	110566	2025/09/18	2026/09/17	BACL Cal	C
WEINSCHEL	10dB Attenuator	5324	AU 3842	2025/03/26	2026/03/25	BACL Cal	C
Unknown	RF Coaxial Cable	No.35	/	2025/05/30	2026/05/29	BACL Cal	C
UNI-T	DC Power Supply	UTP1306 S	2109D0903 324	2025/03/26	2026/03/25	BACL Cal	C

*** Statement of Traceability:** Shenzhen Accurate Technology Co., Ltd. attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Note

A. Calibration conducted by the National Institute of Information and Communications Technology (NICT) (hereinafter referred to as"NICT")or a designated calibration agency under Article 102-18 paragraph (1)

B. Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No.51of1992)

C. Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph(1)

D.Calibration conducted by using measuring instruments and other equipment which shall have been given any of calibration, etc. listed above from A to C.

FREQUENCY TOLERANCE

Limit

- 50ppm or below

Test Procedure

Set the EUT to the measurement frequency without modulation.

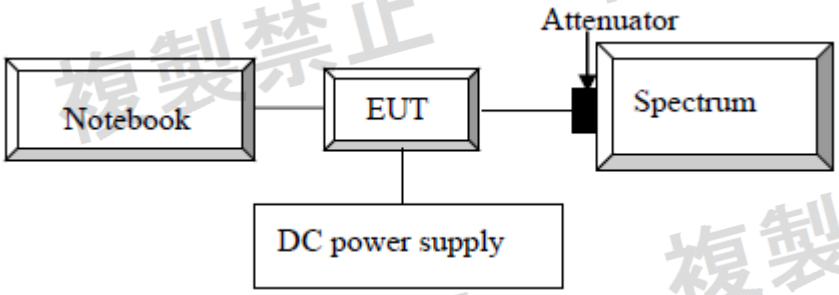
Setting of SA is following as:

- Center Frequency: Frequency to measure
- RBW: 1kHz, VBW: 3kHz
- Span: 300kHz
- Sweep time: Auto or more
- Log scale: 10dB/Div, Data points: 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak
- Sweep mode: Continuous Sweep
- Marker: Spot

Record the peak spot frequency.

If the EUT can't set at un-modulation mode, measure the 10dBc center frequency.

Measurement System Diagram



Test Data

EUT operation mode: Transmitting

Test Result: Please refer to the Appendix.

OCCUPIED BANDWIDTH

Limit

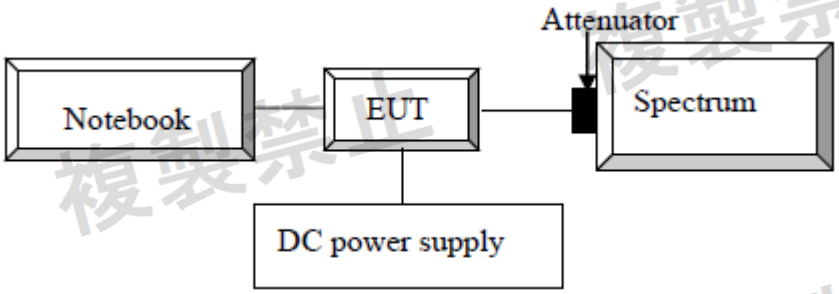
- Occupied bandwidth: FH≤83.5 MHz; OFDM, DS≤26 MHz; Others≤26 MHz

Test Procedure

1. Setting of SA is following as:
   - Center Frequency: Frequency to measure
   - RBW: 30 kHz, VBW: 30 kHz
   - Span: 2.5MHz/5MHz
   - Sweep time: Auto or more
   - Log scale: 10dB/Div, Data points: 400 points or more
   - Reference level: Enough level for maximum dynamic range
   - Detection: Positive Peak
   - Sweep mode: Continuous Sweep
   - Marker: Spot

2. EUT have transmitted the maximum modulation signal and fixed channelize. SA set to 99% of occupied bandwidth to measure occupied bandwidth.

Measurement System Diagram



Test Data

EUT operation mode: Transmitting

Test Result: Please refer to the Appendix.

TRANSMITTER SPURIOUS EMISSION STRENGTH AND UNWANTED EMISSION INTENSITY

Limit

Frequency Band	Limit
Band I: 30MHz-1GHz	0.25μW/100kHz (-36dBm/100kHz)
Band II: 1GHz-2387MHz	2.5μW/MHz (-26dBm/MHz)
Band III: 2387MHz-2400MHz	25μW/MHz (-16dBm/MHz)
Band IV: 2483.5MHz-2496.5MHz	25μW/MHz (-16dBm/MHz)
Band V: 2496.5MHz-12.5GHz	2.5μW/MHz (-26dBm/MHz)

Test Procedure

Conditions of Application Equipment (EUT)

- The modulation state shall be in continuously transmitting mode.

Spectrum Analyzer Conditions:

- Span: Measuring Frequency Range
- RBW: 1MHz (frequency range; 1GHz over), 100kHz (frequency range; 30MHz to 1GHz)
- VBW: Same as RBW (1MHz or 100kHz)
- Sweep time: Auto(Minimum time to ensure measurement accuracy.)
- Data points: 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak

If the measured value is under the technical standard value, do not need to measure more detail.

If above test over the limit, the below test procedure should be used:

Step 1: Center the frequency which was want to investigate, search the peak frequency.

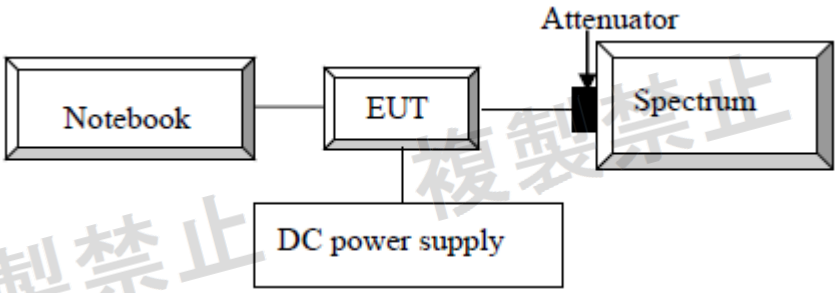
Step 2: Center frequency: Searched Frequency

- Span: 0Hz
- RBW: 1MHz(Above 1GHz), VBW: Same as RBW.
- Sweep time: Auto(Minimum time to ensure measurement accuracy.

*In case of burst wave, one burst shall be included per data point)

- Data points: 400 points or more.
- Sweep mode: Single Sweep.
- Detection Mode: Sample

Measurement System Diagram



Test Data

EUT operation mode: Transmitting

Test Result: Please refer to the Appendix.

ANTENNA OUTPUT POWER AND ANTENNA POWER TOLERANCE

Limit

- ≤ 10 mW/MHz (OFDM (20MHz system), DSSS from 2400-2483.5 MHz)
- ≤ 5 mW/MHz (OFDM (40MHz system) from 2400-2483.5 MHz)
- ≤ 10 mW (other from 2400-2483.5 MHz)

The Output Power Tolerance must be within +20%, -80%.

EIRP

- ≤ 12.14dBm/MHz (OFDM(20MHz system),DSSS from 2400-2483.5MHz)
- ≤ 9.13dBm/MHz (OFDM(40MHz system), from 2400-2483.5MHz)
- ≤12.14dBm (other from 2400-2483.5MHz)

Test Procedure

Step 1: Measure the total power by Power Meter in a state of non-hopping mode (with Average Sensor)

Step 2: If it's the burst wave, please measure the burst ratio. Then calculate the real total power by burst ratio.

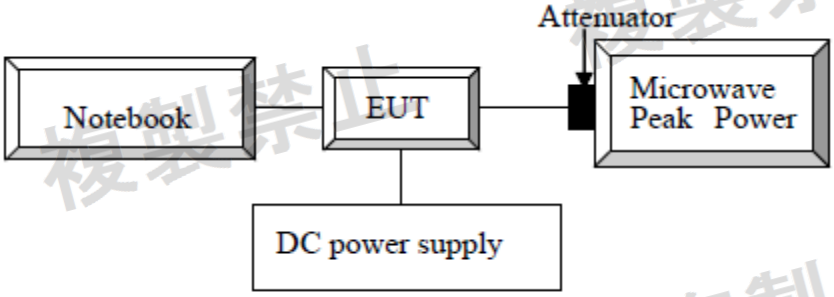
Step 3: Calculate the mean power.

Antenna output power (mW) = Antenna output power Reading (mW) / Burst Ratio

Note: The burst ratio has been calculated to result by power meter, so the equation updated as below:

Antenna output power (mW) = Antenna output power Reading (mW)

Measurement System Diagram



Test Data

EUT operation mode: Transmitting

Test Result: Please refer to the Appendix.

RECEIVER SPURIOUS EMISSION AND UNWANTED EMISSION INTENSITY

Limit

Frequency Band	Limit
Band I: 30MHz-1GHz	4nW (-54dBm)
Band II: 1GHz-12.5GHz	20nW (-47dBm)

Test Procedure

Conditions of Application Equipment (EUT)

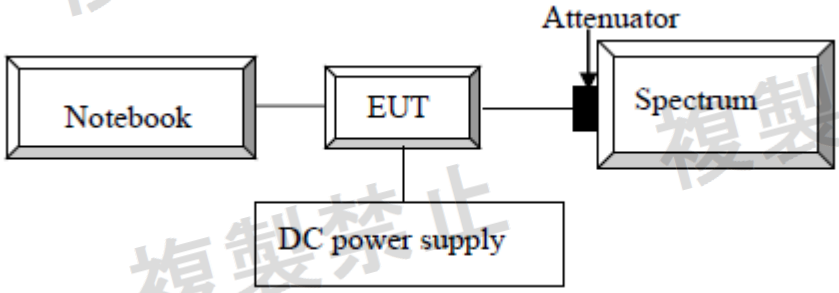
- The modulation state shall be “continuous receiving mode”.

Spectrum Analyzer Conditions

- Start Frequency: Start Frequency of frequency range to measure (30MHz or 1GHz)
- Stop Frequency: Stop Frequency of frequency range to measure (1GHz or 12.5GHz)
- Span: AUTO (Measurement Range)
- RBW: 100 kHz, VBW: 100 kHz for Frequency < 1 GHz
- RBW: 1MHz, VBW: 1MHz for Frequency > 1 GHz
- Sweep time: AUTO or more
- Sweep mode: Auto Sweep
- Detection: Positive Peak
- Reference Level: Enough level for maximum dynamic range

If searched value is under the technical standard value, do not need to measure more detail.

Measurement System Diagram



Test Data

EUT operation mode: Receiving

Test Result: Please refer to the Appendix.

INTERFERENCE PREVENTION FUNCTION

Requirement

The EUT shall have the interference prevention capability to transmit or to receive the identification automatically, so that sender and receiver shall exclude other equipment.

Test Procedure

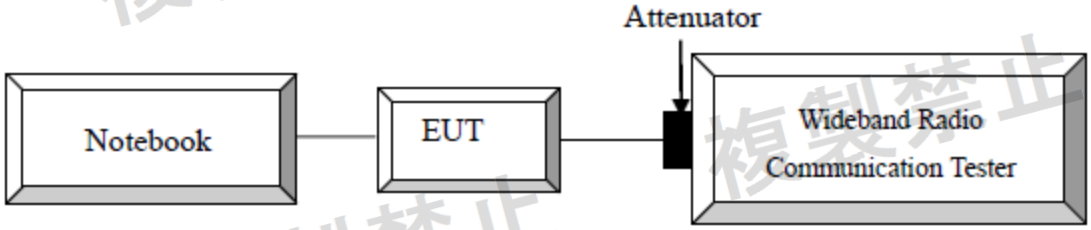
In the case that the EUT has the function of automatically transmitting the identification code:

1. Transmit the predetermined identification codes from EUT
2. Check the transmitted identification codes with the demodulator.

In the case of receiving the identification codes:

1. Transmit the predetermined identification codes from the counterpart.
2. Check if communication is normal
3. Transmit the signal other than predetermined ID codes from the counterpart.
4. Check if the EUT stops the transmission, or if it displays that identification codes are different from the predetermined ones.

Measurement System Diagram



Test Data

Test Result: Please refer to the Appendix.

CONSTRUCTION PROTECTION CONFIRMATION

Limit

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily.

Confirmation Method

The device is tightly fastened with special buckle and is difficult to open. Please refer to the actual photo.

APPENDIX

Test Information:

Sample No.:	3AWK-2	**Test Date:**	2025/10/20
Test Site:	RF	**Test Mode:**	Transmitting/Receiving
Tester:	Cayde Hou	**Test Result:**	Pass

Environmental Conditions:

Temperature: (°C)	25.3	**Relative Humidity: (%)**	49	**ATM Pressure: (kPa)**	100.7

Frequency Error

Test Condition: TC1

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.97645	-9.80	± 50	Pass
	2440	2439.97645	-9.65		Pass
	2480	2479.97585	-9.74		Pass

Test Condition: TC2

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.97645	-9.80	± 50	Pass
	2440	2439.97645	-9.65		Pass
	2480	2479.97585	-9.74		Pass

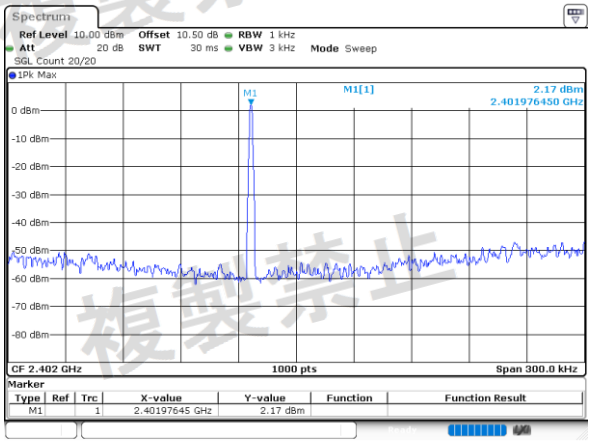
Test Condition: TC3

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.97735	-9.43	± 50	Pass
	2440	2439.97675	-9.53		Pass
	2480	2479.97645	-9.50		Pass

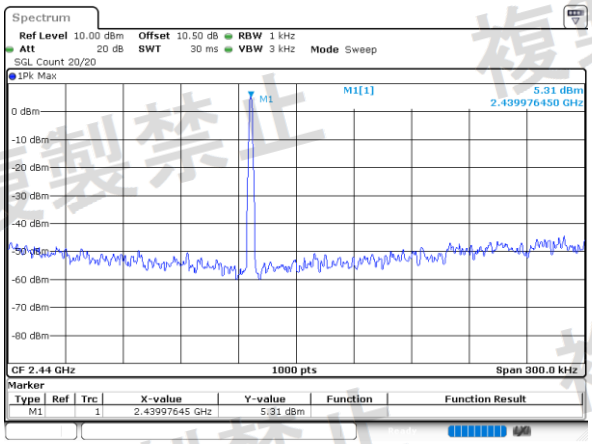
Frequency Tolerance = (Measure Frequency - Frequency)/Frequency*10^6

Test Condition: TC1

2402MHz

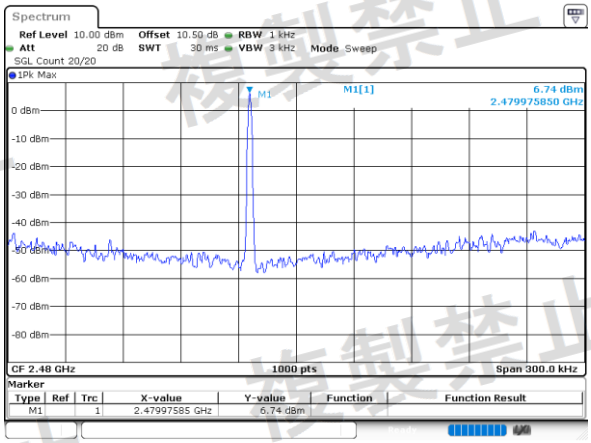


2440MHz

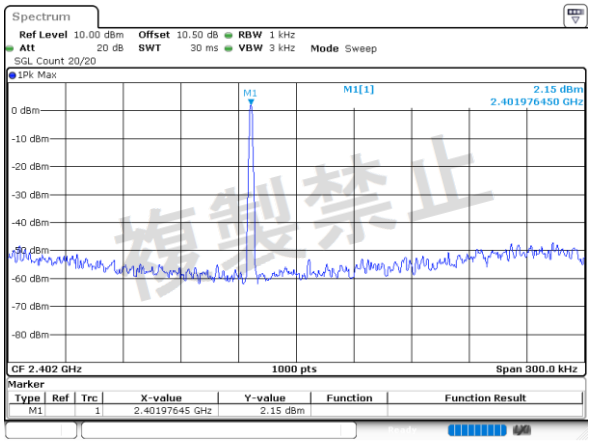


Test Condition: TC2

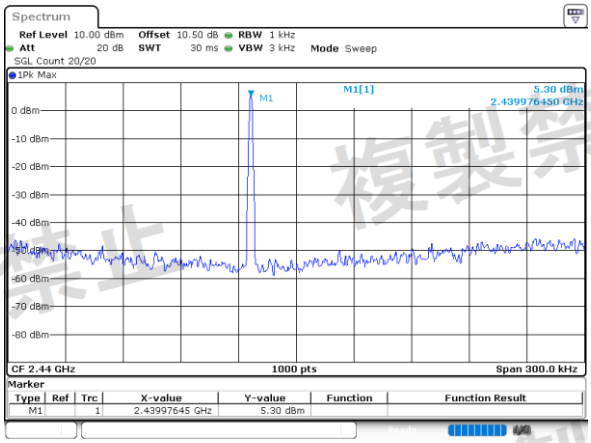
2480MHz



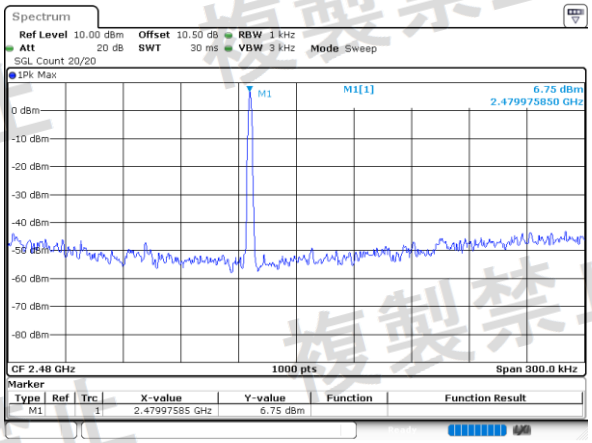
2402MHz



2440MHz

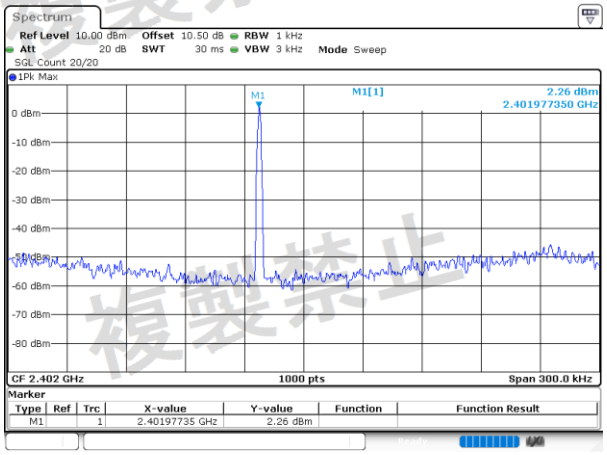


2480MHz

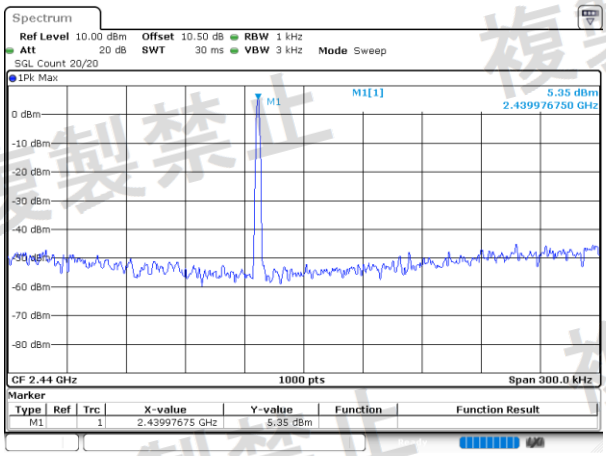


Test Condition: TC3

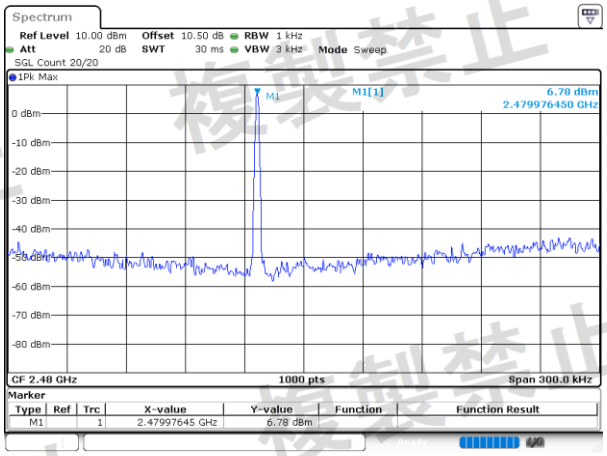
2402MHz



2440MHz



2480MHz



Occupied Bandwidth

Test Condition: TC1

Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.023	1.03	1.03	≤ 26	Pass
BLE 2M	2.045	2.05	2.06		Pass

Test Condition: TC2

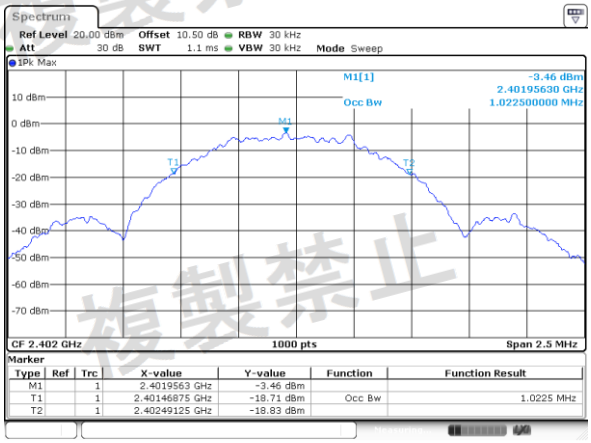
Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.02	1.03	1.03	≤ 26	Pass
BLE 2M	2.045	2.055	2.06		Pass

Test Condition: TC3

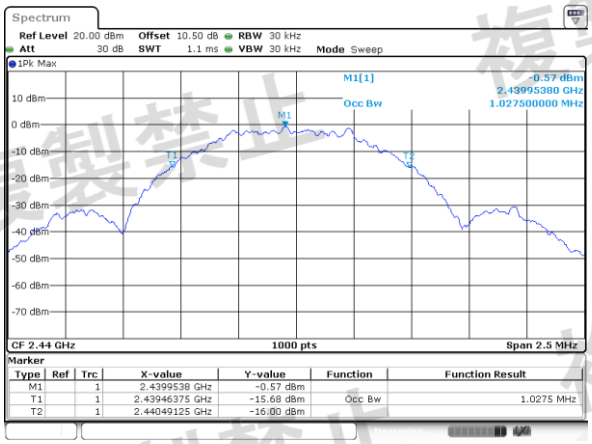
Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.02	1.028	1.033	≤ 26	Pass
BLE 2M	2.045	2.055	2.06		Pass

Test Condition: TC1

BLE 1M_Low Channel

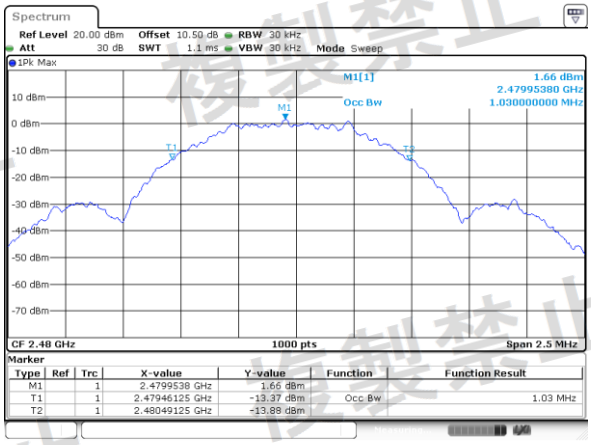


BLE 1M_Middle Channel

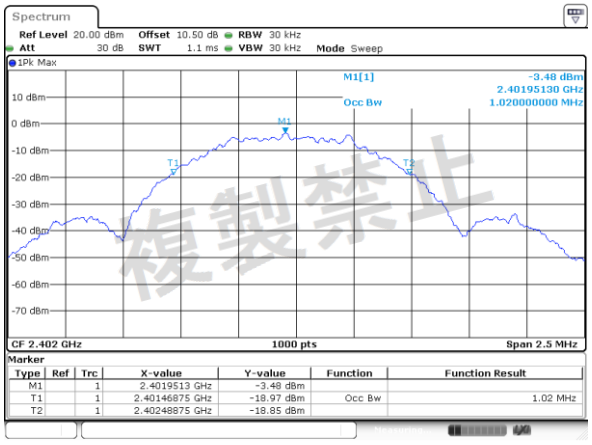


Test Condition: TC2

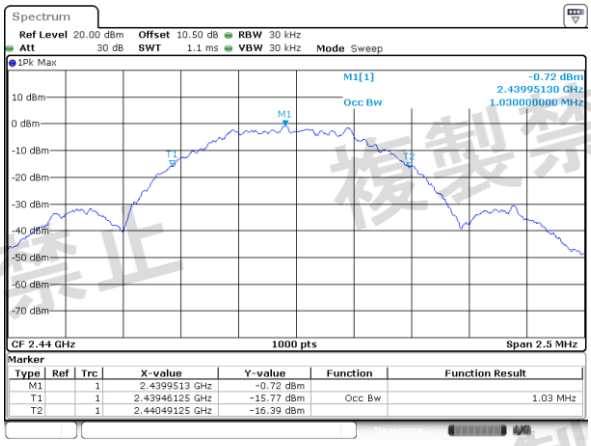
BLE 1M_High Channel



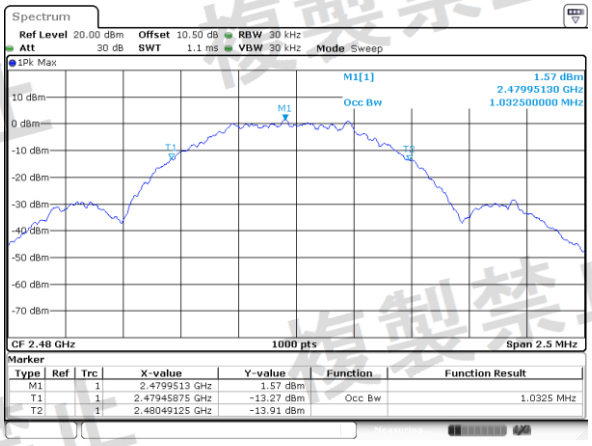
BLE 1M_Low Channel



BLE 1M_Middle Channel

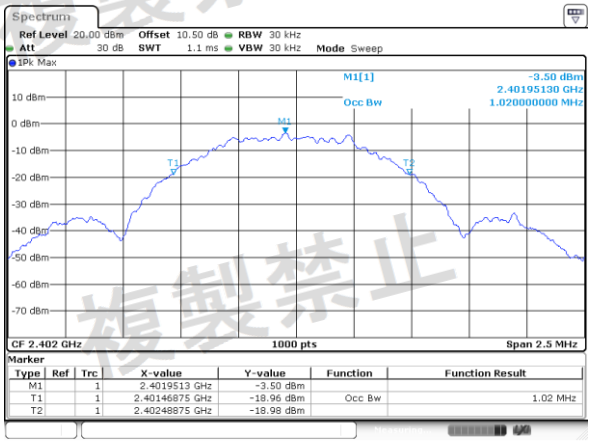


BLE 1M_High Channel

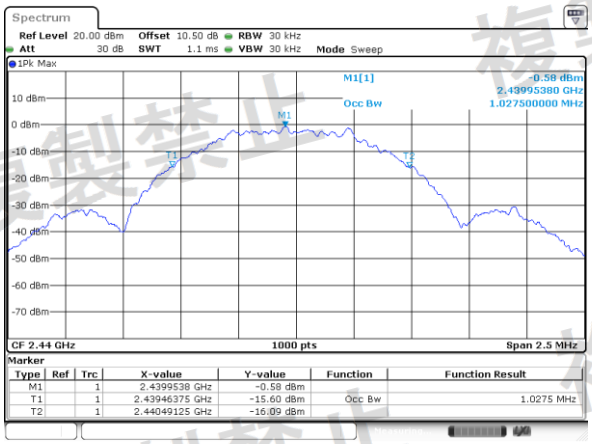


Test Condition: TC3

BLE 1M_Low Channel

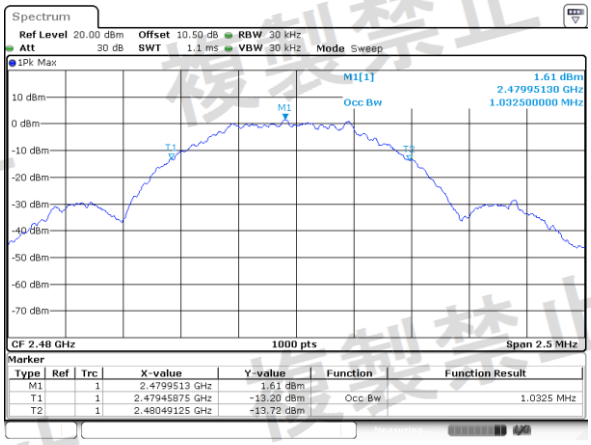


BLE 1M_Middle Channel

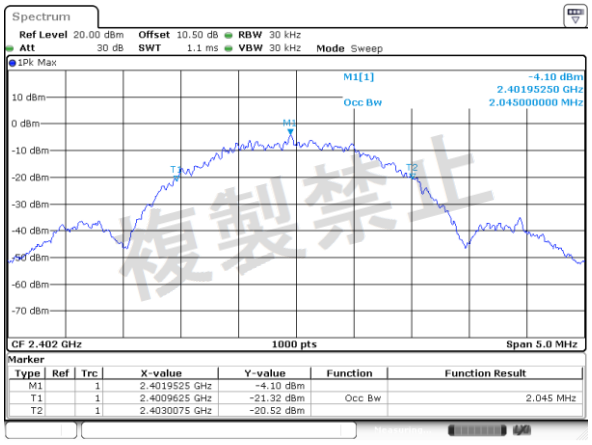


Test Condition: TC1

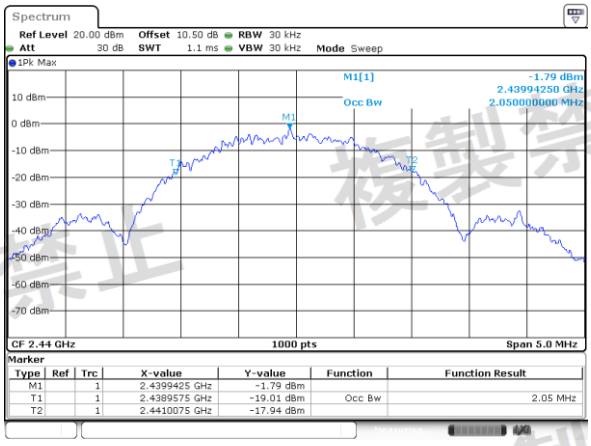
BLE 1M_High Channel



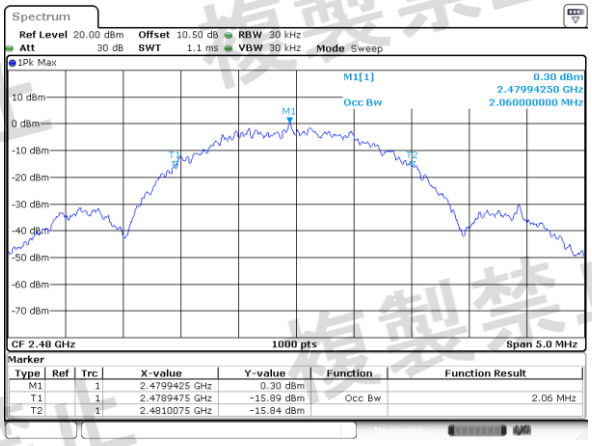
BLE 2M_Low Channel



BLE 2M_Middle Channel

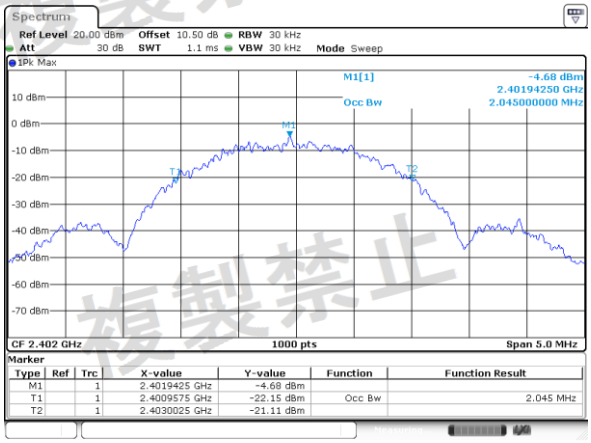


BLE 2M_High Channel

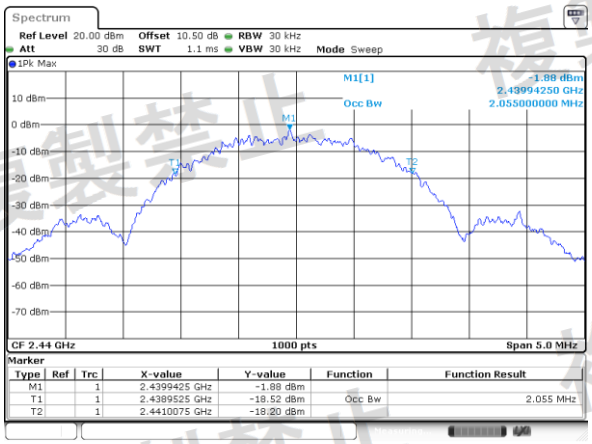


Test Condition: TC2

BLE 2M_Low Channel

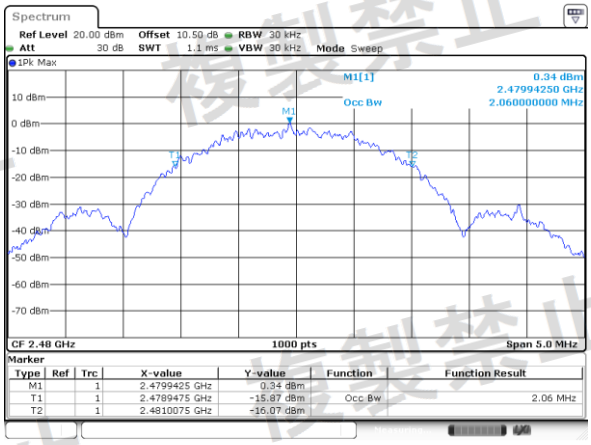


BLE 2M_Middle Channel

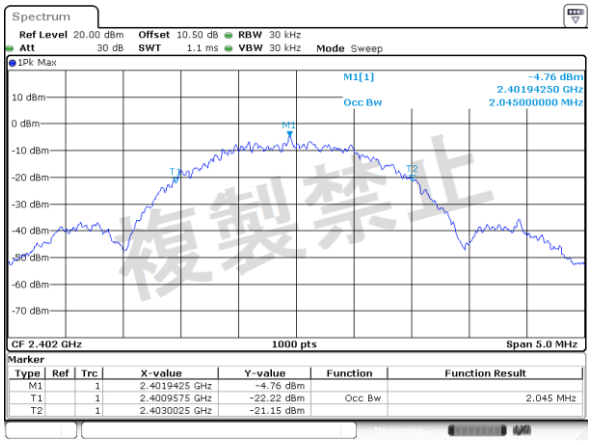


Test Condition: TC3

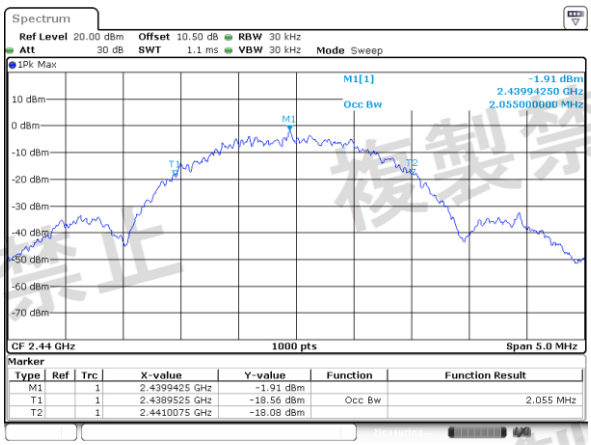
BLE 2M_High Channel



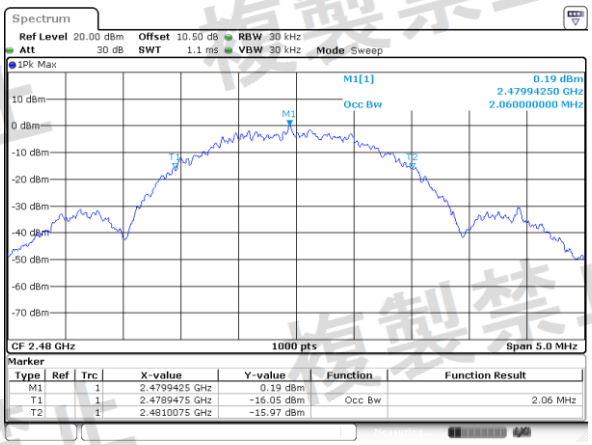
BLE 2M_Low Channel



BLE 2M_Middle Channel



BLE 2M_High Channel



Transmitter Spurious Emission and Unwanted Emission Intensity

Test Condition: TC1, BLE 1M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	954.65	-47.82	0.017	0.25	Pass
	Band II (1MHz)	1000	2387	1150.14	-38.32	0.147	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9838	-32.35	0.582	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2496.3928	-38.12	0.154	25	Pass
	Band V (1MHz)	2496.5	12500	5825.2	-33.60	0.437	2.50	Pass
Middle	Band I (100kHz)	30	1000	842.13	-47.39	0.018	0.25	Pass
	Band II (1MHz)	1000	2387	2305.51	-38.54	0.140	2.50	Pass
	Band III (1MHz)	2387	2400	2396.4348	-37.90	0.162	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2486.7468	-37.95	0.160	25	Pass
	Band V (1MHz)	2496.5	12500	5840.2	-33.06	0.494	2.50	Pass
High	Band I (100kHz)	30	1000	951.74	-47.48	0.018	0.25	Pass
	Band II (1MHz)	1000	2387	2206.34	-38.26	0.149	2.50	Pass
	Band III (1MHz)	2387	2400	2391.9758	-37.99	0.159	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2487.6893	-37.46	0.179	25	Pass
	Band V (1MHz)	2496.5	12500	6960.6	-33.43	0.454	2.50	Pass

Test Condition: TC1, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	482.75	-47.61	0.017	0.25	Pass
	Band II (1MHz)	1000	2387	1578.73	-38.16	0.153	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-20.98	7.980	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2491.7518	-37.65	0.172	25	Pass
	Band V (1MHz)	2496.5	12500	6945.6	-33.38	0.459	2.50	Pass
Middle	Band I (100kHz)	30	1000	879.48	-47.13	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	1589.82	-38.46	0.143	2.50	Pass
	Band III (1MHz)	2387	2400	2390.5523	-37.59	0.174	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.8268	-36.68	0.215	25	Pass
	Band V (1MHz)	2496.5	12500	5775.1	-32.95	0.507	2.50	Pass
High	Band I (100kHz)	30	1000	936.22	-47.78	0.017	0.25	Pass
	Band II (1MHz)	1000	2387	2120.35	-38.05	0.157	2.50	Pass
	Band III (1MHz)	2387	2400	2398.5863	-38.19	0.152	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.5098	-34.36	0.366	25	Pass

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
High	Band V (1MHz)	2496.5	12500	7000.6	-33.85	0.412	2.50	Pass

Test Condition: TC2, BLE 1M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	988.6	-47.59	0.017	0.25	Pass
	Band II (1MHz)	1000	2387	2153.64	-38.52	0.141	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-31.73	0.671	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.5238	-37.54	0.176	25	Pass
	Band V (1MHz)	2496.5	12500	6995.6	-33.01	0.500	2.50	Pass
Middle	Band I (100kHz)	30	1000	896.45	-46.75	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	2158.49	-38.21	0.151	2.50	Pass
	Band III (1MHz)	2387	2400	2396.1423	-38.07	0.156	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2489.3598	-37.89	0.163	25	Pass
	Band V (1MHz)	2496.5	12500	6950.6	-33.37	0.460	2.50	Pass
High	Band I (100kHz)	30	1000	965.32	-47.59	0.017	0.25	Pass
	Band II (1MHz)	1000	2387	1030.86	-38.37	0.146	2.50	Pass
	Band III (1MHz)	2387	2400	2389.0508	-37.89	0.163	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2486.2138	-37.32	0.185	25	Pass
	Band V (1MHz)	2496.5	12500	6665.5	-33.83	0.414	2.50	Pass

Test Condition: TC2, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	776.66	-46.82	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	2148.78	-38.13	0.154	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-21.31	7.396	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2493.7798	-37.11	0.195	25	Pass
	Band V (1MHz)	2496.5	12500	5835.2	-32.59	0.551	2.50	Pass
Middle	Band I (100kHz)	30	1000	888.21	-47.61	0.017	0.25	Pass
	Band II (1MHz)	1000	2387	2198.02	-38.37	0.146	2.50	Pass
	Band III (1MHz)	2387	2400	2389.4603	-37.83	0.165	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.0398	-37.57	0.175	25	Pass
	Band V (1MHz)	2496.5	12500	6475.4	-33.25	0.473	2.50	Pass
High	Band I (100kHz)	30	1000	933.31	-47.22	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	1891.49	-38.10	0.155	2.50	Pass

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
High	Band III (1MHz)	2387	2400	2391.3843	-37.65	0.172	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.5553	-35.30	0.295	25	Pass
	Band V (1MHz)	2496.5	12500	6610.4	-33.80	0.417	2.50	Pass

Test Condition: TC3, BLE 1M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	910.52	-46.91	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	2217.44	-38.15	0.153	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-31.93	0.641	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2492.7528	-37.58	0.175	25	Pass
	Band V (1MHz)	2496.5	12500	5820.2	-33.15	0.484	2.50	Pass
Middle	Band I (100kHz)	30	1000	977.93	-46.72	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	1753.49	-37.73	0.169	2.50	Pass
	Band III (1MHz)	2387	2400	2395.1673	-38.28	0.149	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.7548	-38.01	0.158	25	Pass
	Band V (1MHz)	2496.5	12500	6290.3	-33.57	0.440	2.50	Pass
High	Band I (100kHz)	30	1000	985.69	-47.15	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	2139.07	-38.80	0.132	2.50	Pass
	Band III (1MHz)	2387	2400	2390.8643	-38.51	0.141	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2486.9093	-37.60	0.174	25	Pass
	Band V (1MHz)	2496.5	12500	6050.2	-33.82	0.415	2.50	Pass

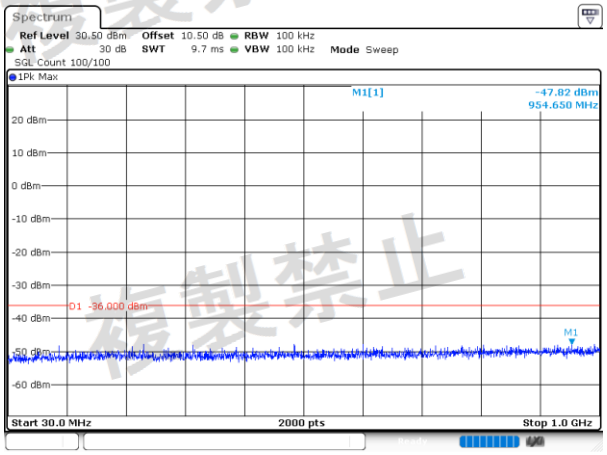
Test Condition: TC3, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	819.82	-46.67	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2217.44	-38.43	0.144	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-21.19	7.603	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2491.2513	-37.09	0.195	25	Pass
	Band V (1MHz)	2496.5	12500	5870.2	-32.77	0.528	2.50	Pass
Middle	Band I (100kHz)	30	1000	898.39	-46.81	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	1943.51	-38.57	0.139	2.50	Pass
	Band III (1MHz)	2387	2400	2397.6243	-37.64	0.172	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2489.3078	-37.93	0.161	25	Pass
	Band V (1MHz)	2496.5	12500	5940.2	-32.52	0.560	2.50	Pass

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
High	Band I (100kHz)	30	1000	802.85	-47.44	0.018	0.25	Pass
	Band II (1MHz)	1000	2387	2121.04	-38.35	0.146	2.50	Pass
	Band III (1MHz)	2387	2400	2399.8733	-38.40	0.145	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.5293	-34.66	0.342	25	Pass
	Band V (1MHz)	2496.5	12500	5875.2	-33.06	0.494	2.50	Pass

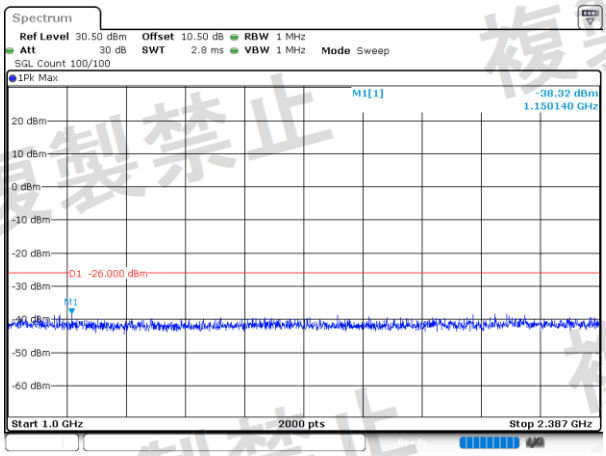
Test Condition: TC1

BLE 1M_Low Channel(30MHz~1GHz)



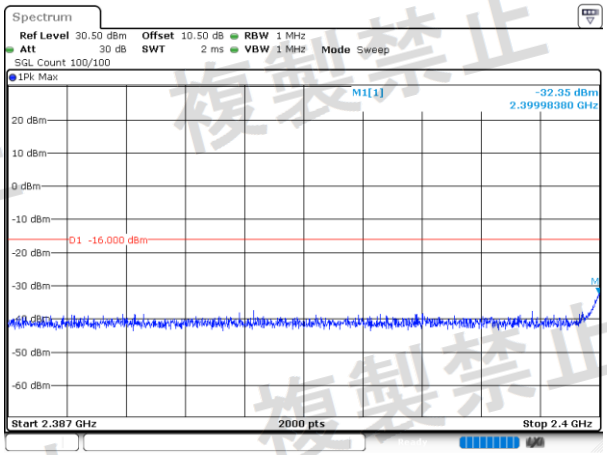
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:26:07

BLE 1M_Low Channel(1GHz~2.387GHz)



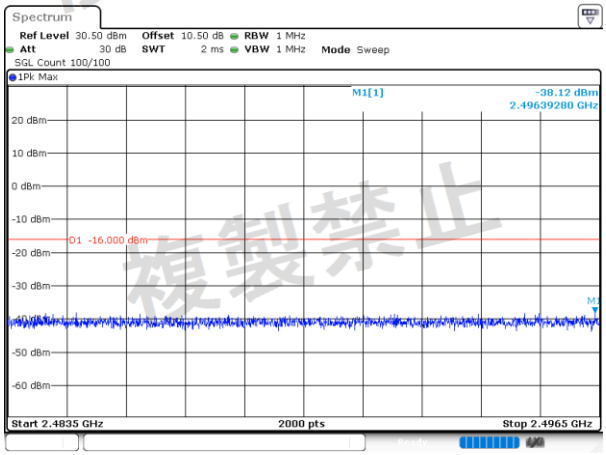
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:26:14

BLE 1M_Low Channel(2.387GHz~2.4GHz)



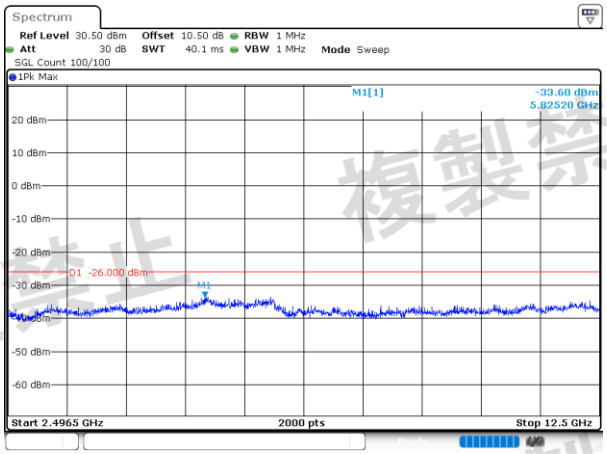
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:26:19

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



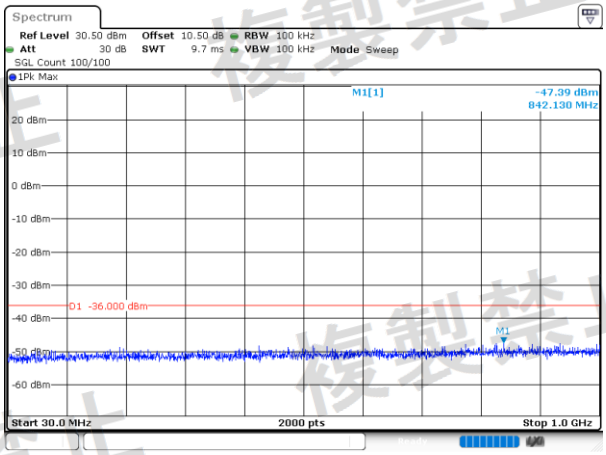
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:26:24

BLE 1M_Low Channel(2.4965GHz~12.5GHz)



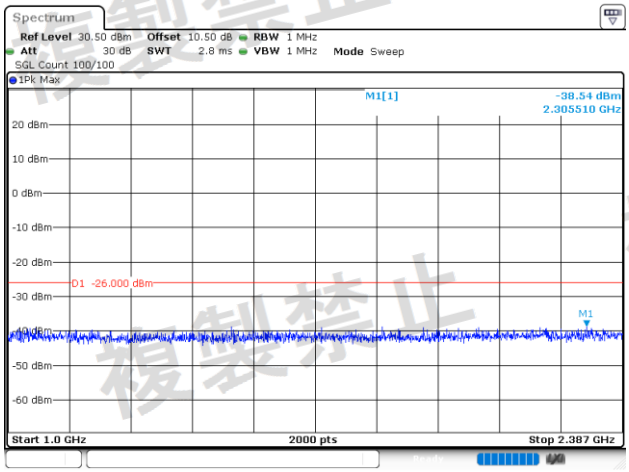
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:26:44

BLE 1M_Middle Channel(30MHz~1GHz)



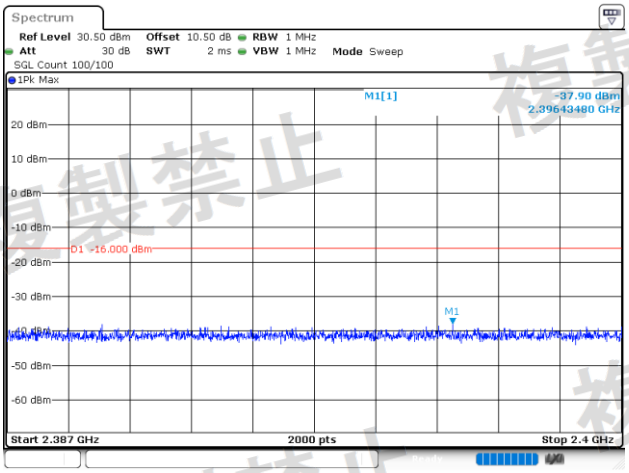
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:27:52

BLE 1M_Middle Channel(1GHz~2.387GHz)



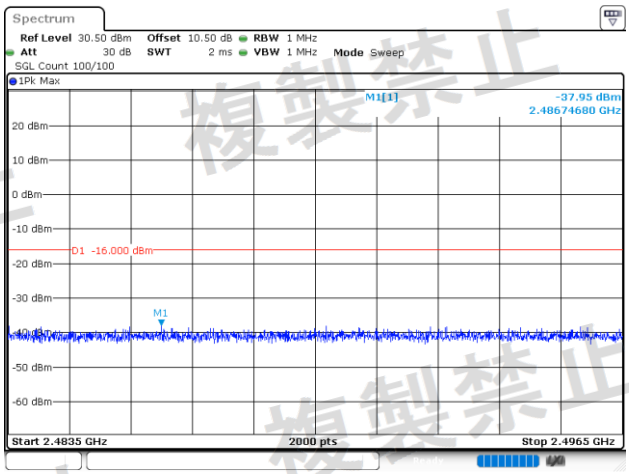
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:27:59

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



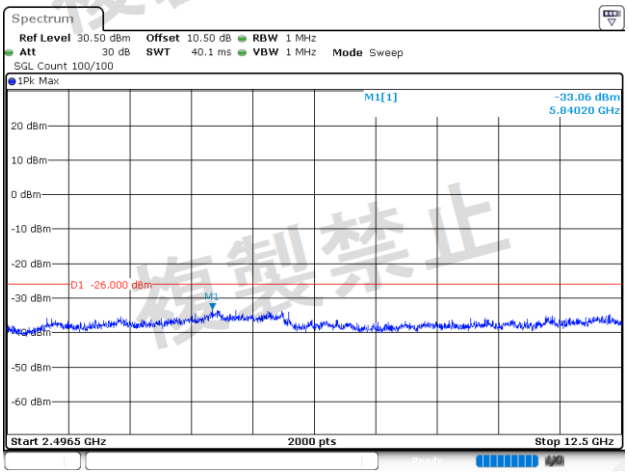
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:28:04

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



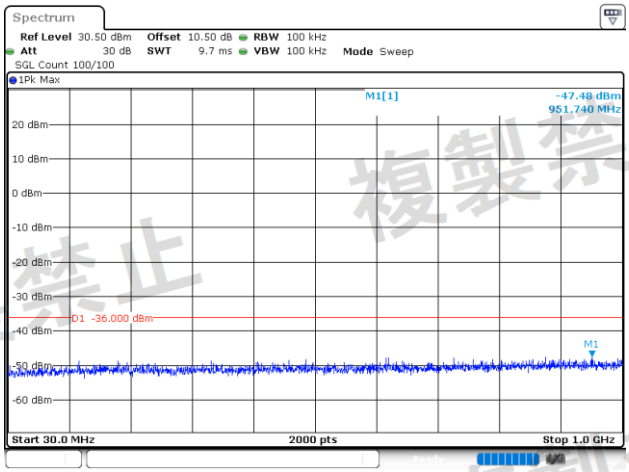
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:28:09

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



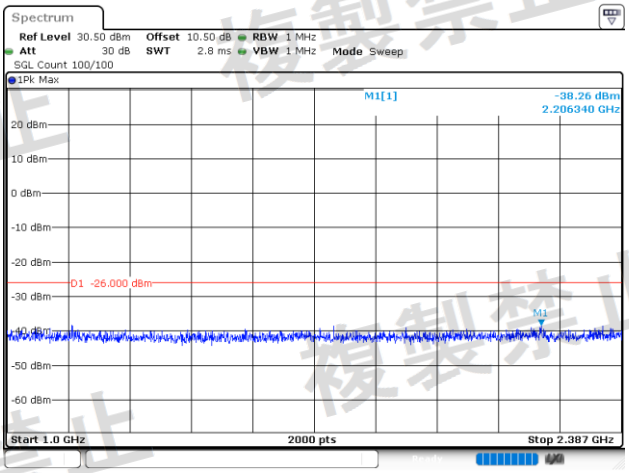
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:28:30

BLE 1M_High Channel(30MHz~1GHz)



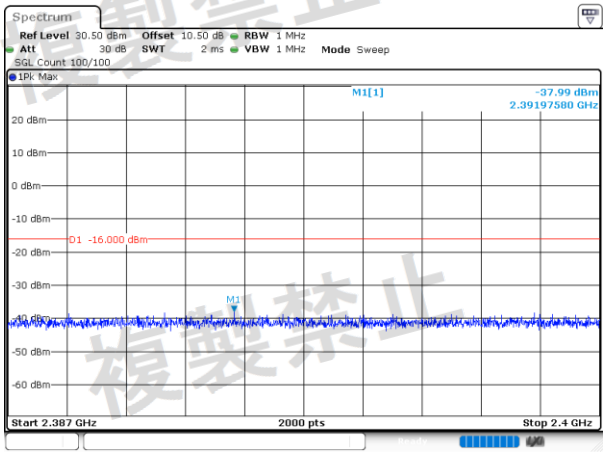
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:29:42

BLE 1M_High Channel(1GHz~2.387GHz)



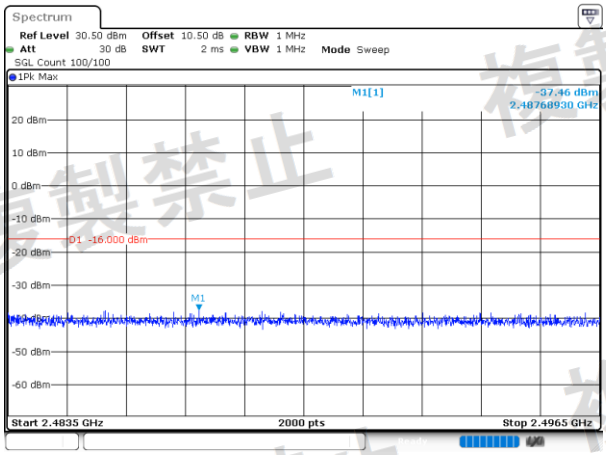
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:29:49

BLE 1M_High Channel(2.387GHz~2.4GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:29:55

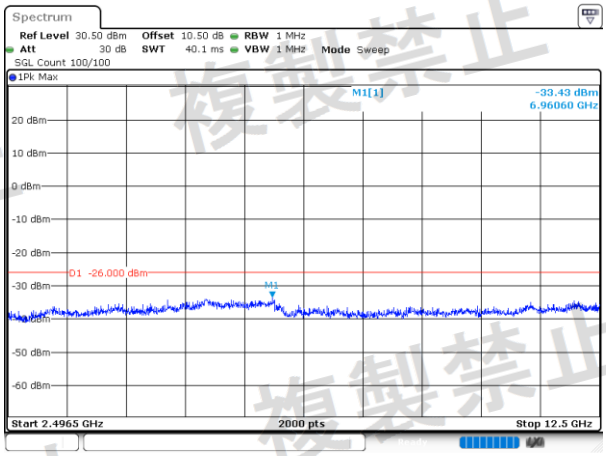
BLE 1M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:29:59

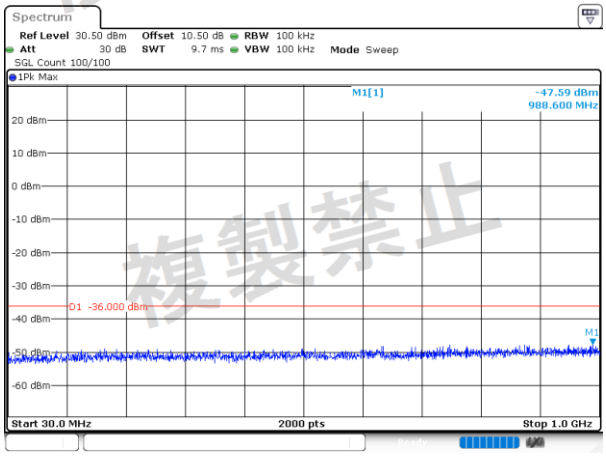
Test Condition: TC2

BLE 1M_High Channel(2.4965GHz~12.5GHz)



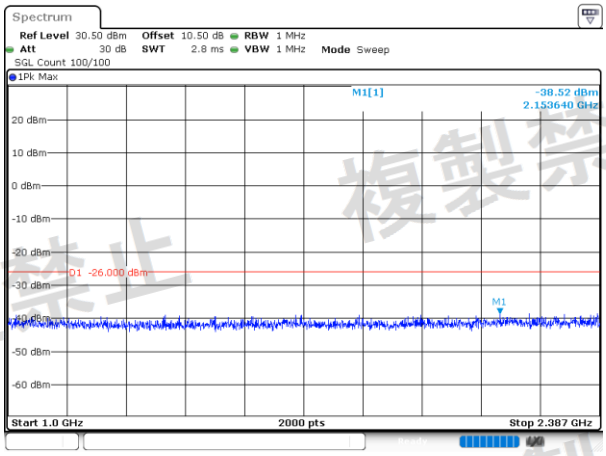
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:30:20

BLE 1M_Low Channel(30MHz~1GHz)



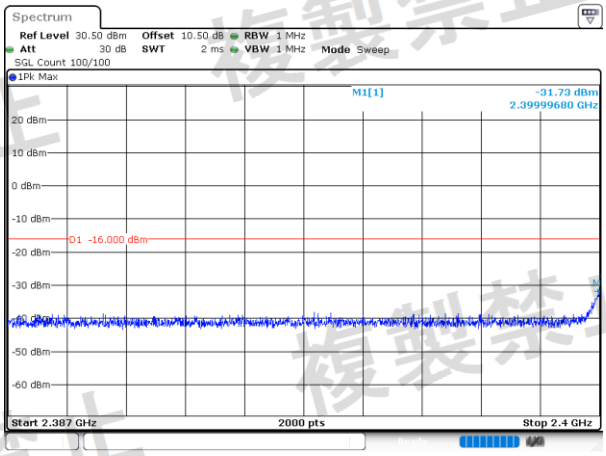
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:50:58

BLE 1M_Low Channel(1GHz~2.387GHz)



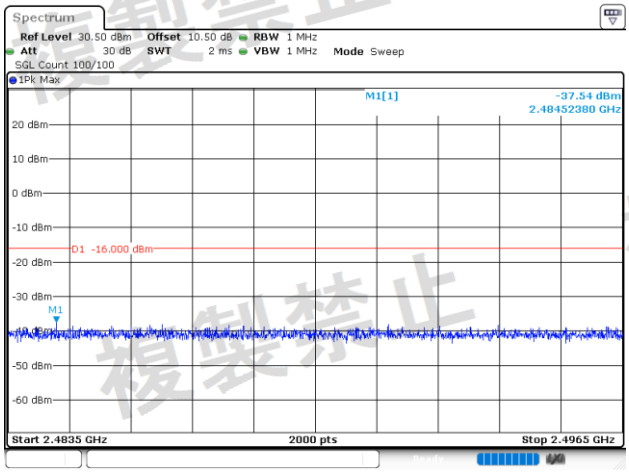
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:51:07

BLE 1M_Low Channel(2.387GHz~2.4GHz)



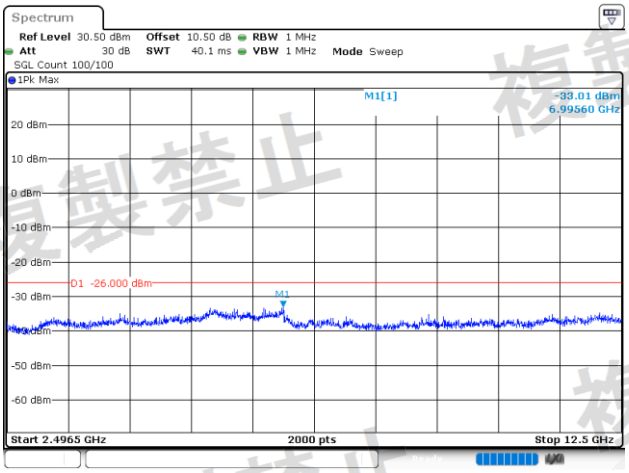
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:51:13

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



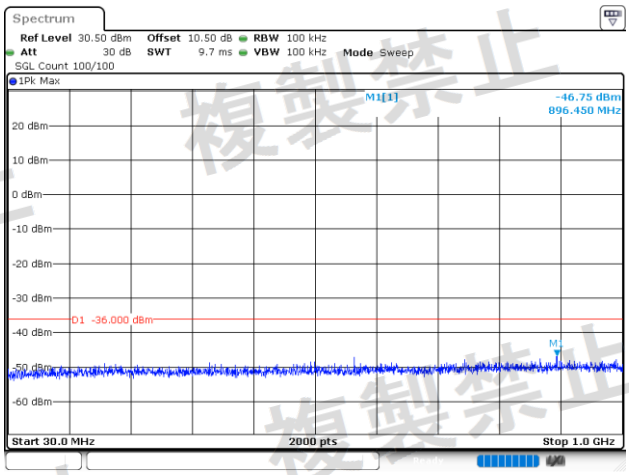
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:51:19

BLE 1M_Low Channel(2.4965GHz~12.5GHz)



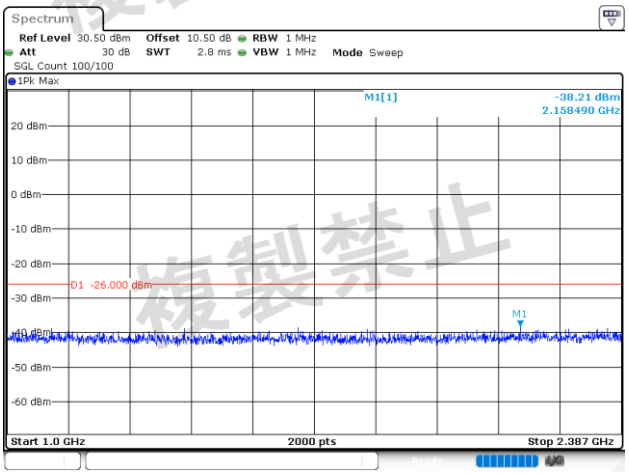
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:51:41

BLE 1M_Middle Channel(30MHz~1GHz)



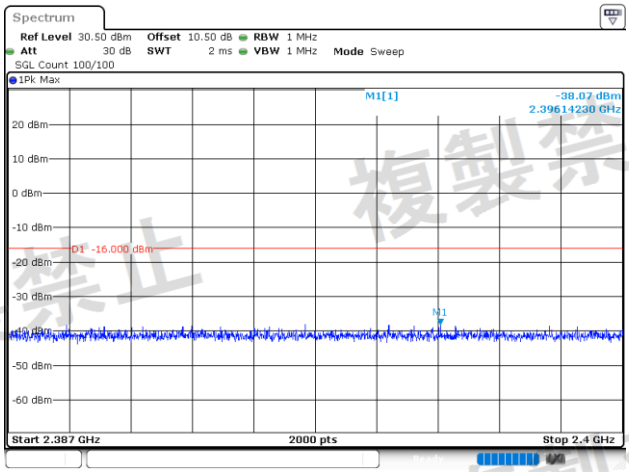
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:08:33

BLE 1M_Middle Channel(1GHz~2.387GHz)



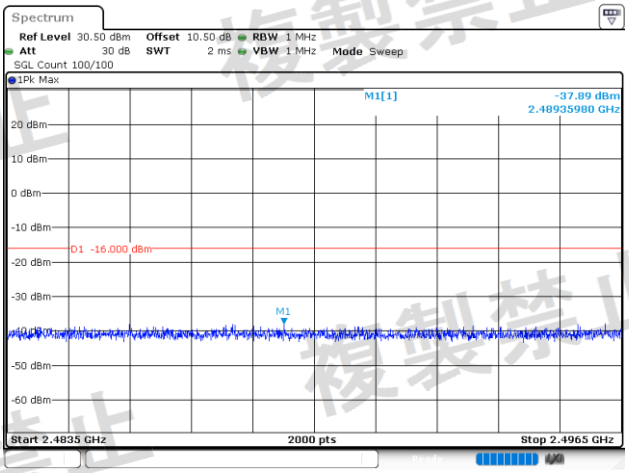
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:08:40

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



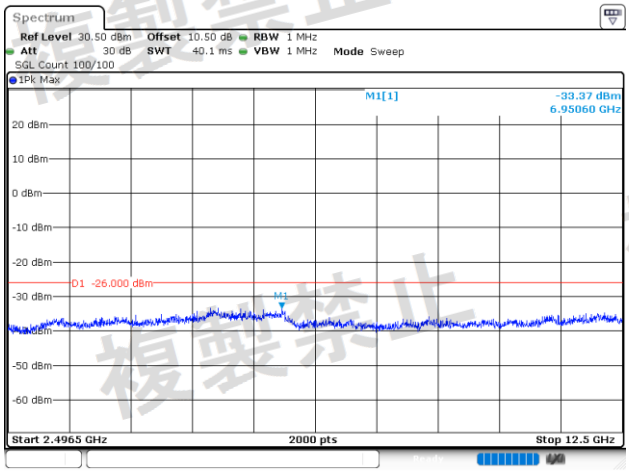
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:08:44

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



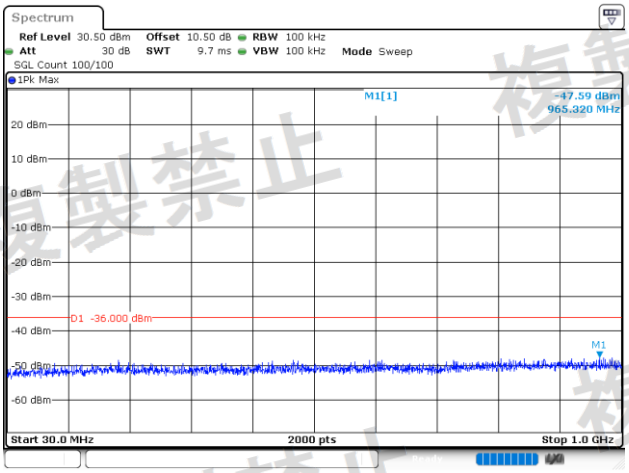
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:08:48

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



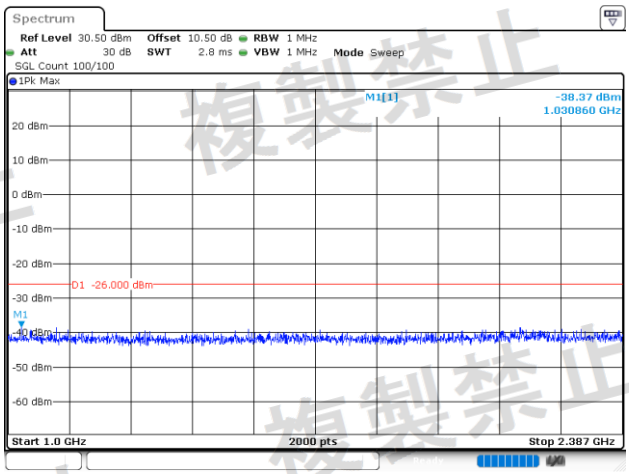
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:09:07

BLE 1M_High Channel(30MHz~1GHz)



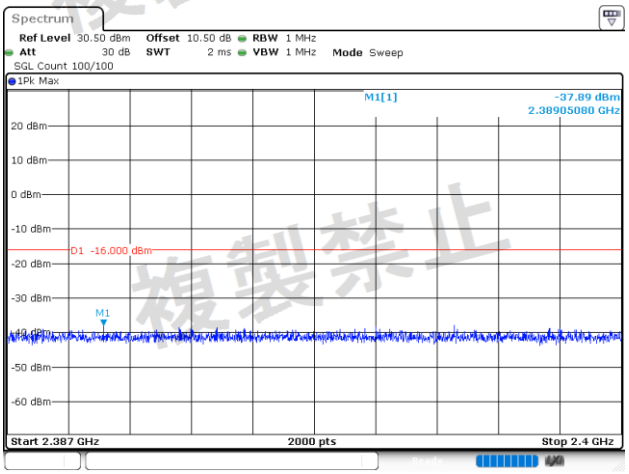
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:11:22

BLE 1M_High Channel(1GHz~2.387GHz)



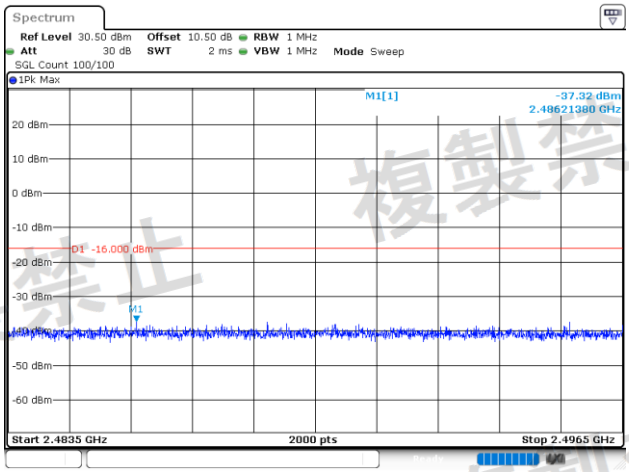
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:11:28

BLE 1M_High Channel(2.387GHz~2.4GHz)



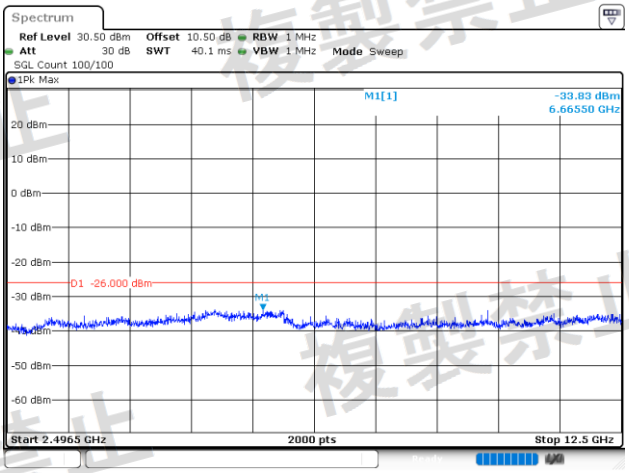
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:11:32

BLE 1M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:11:36

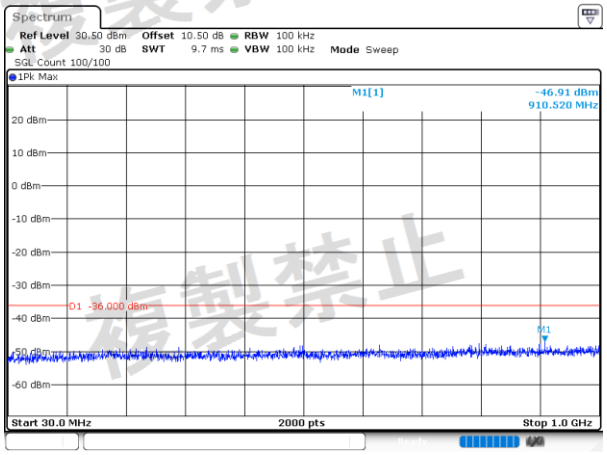
BLE 1M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:11:56

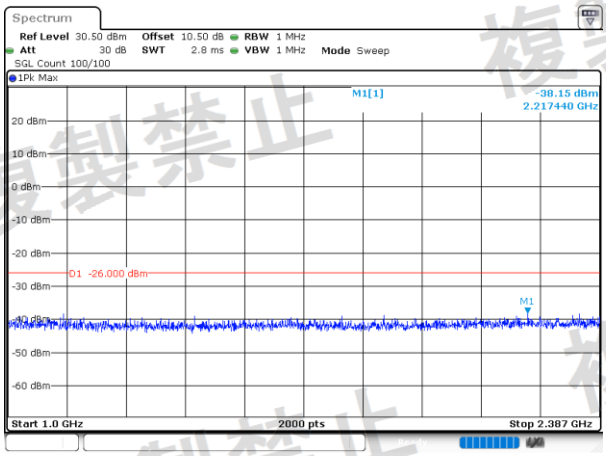
Test Condition: TC3

BLE 1M_Low Channel(30MHz~1GHz)



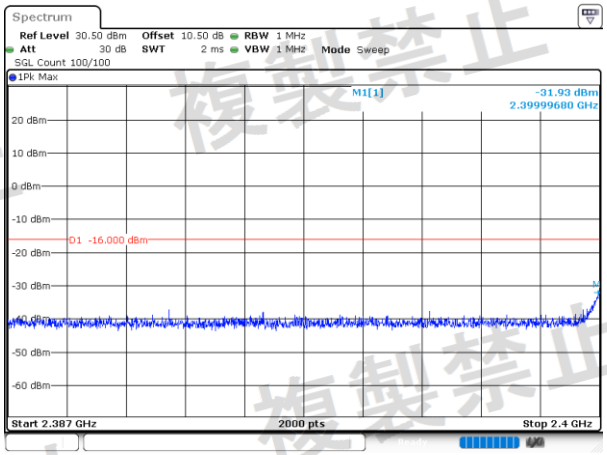
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:22:08

BLE 1M_Low Channel(1GHz~2.387GHz)



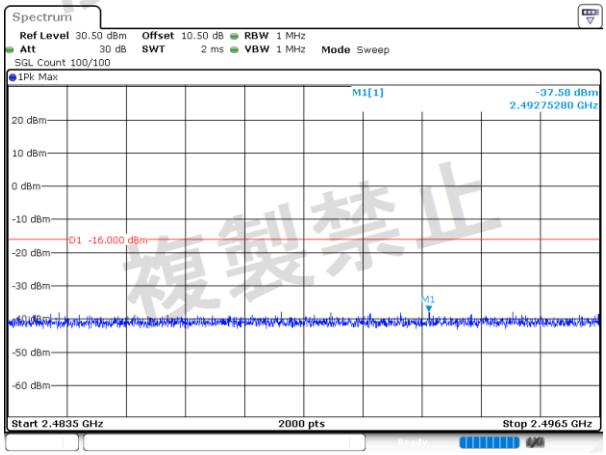
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:22:15

BLE 1M_Low Channel(2.387GHz~2.4GHz)



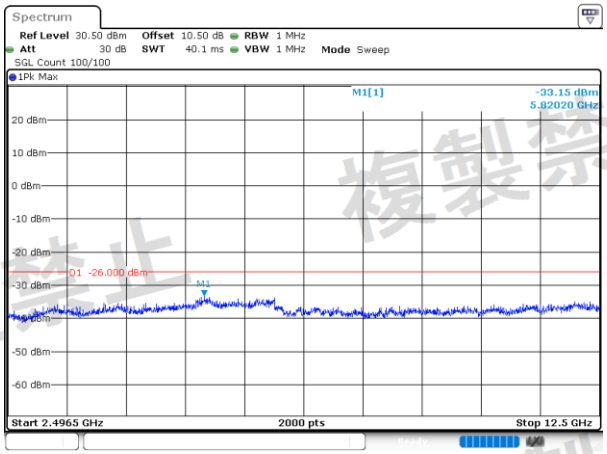
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:22:20

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



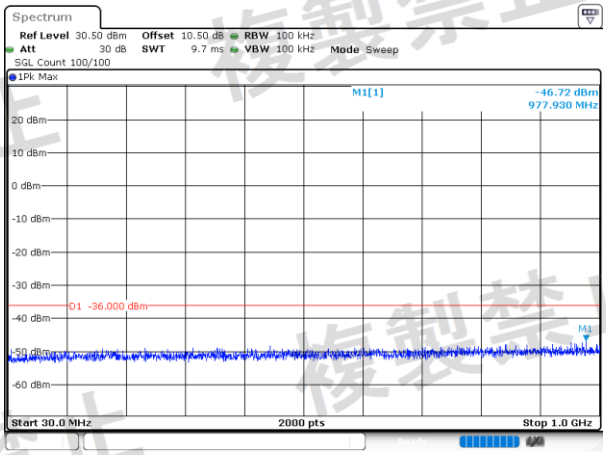
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:22:25

BLE 1M_Low Channel(2.4965GHz~12.5GHz)



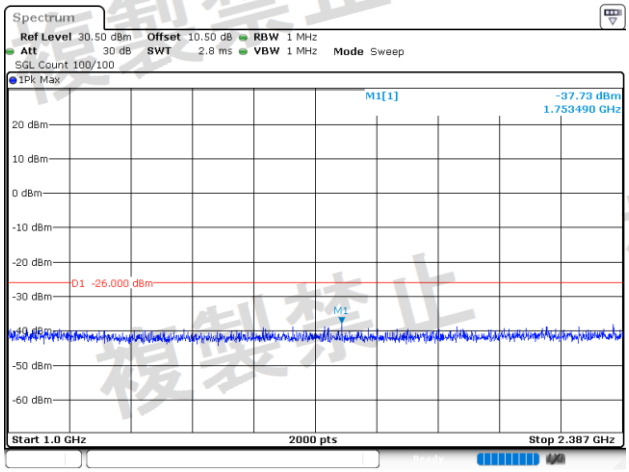
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:22:45

BLE 1M_Middle Channel(30MHz~1GHz)



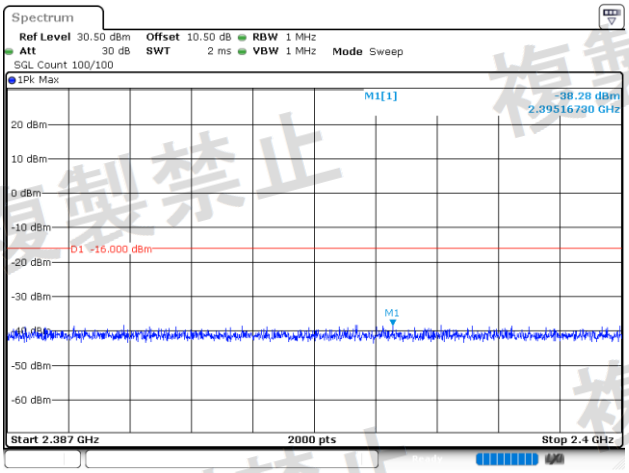
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:24:24

BLE 1M_Middle Channel(1GHz~2.387GHz)



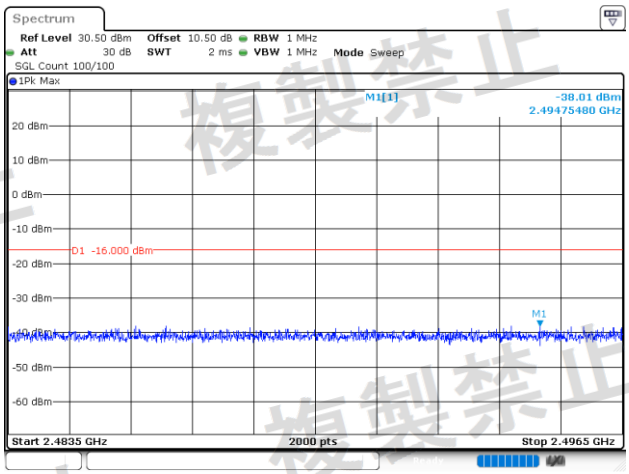
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:24:32

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



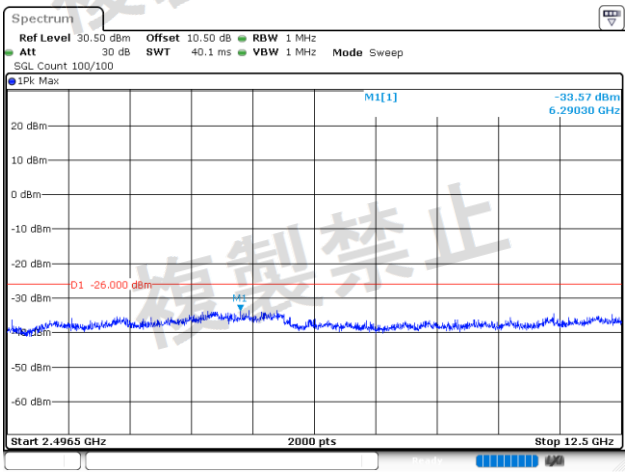
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:24:36

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



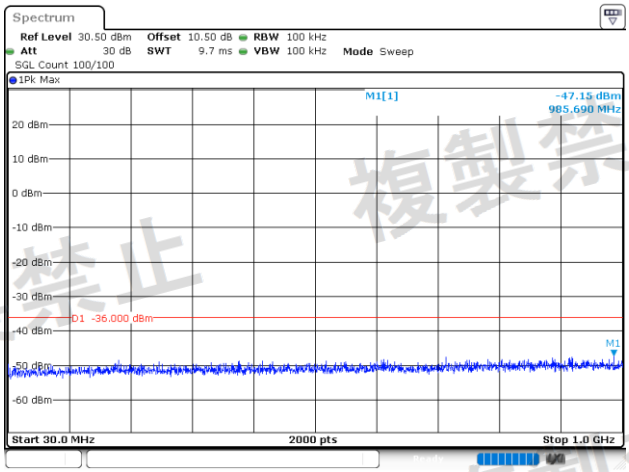
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:24:41

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



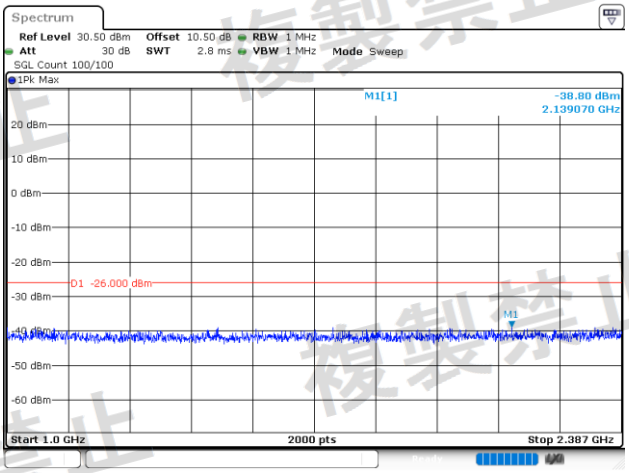
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:25:01

BLE 1M_High Channel(30MHz~1GHz)



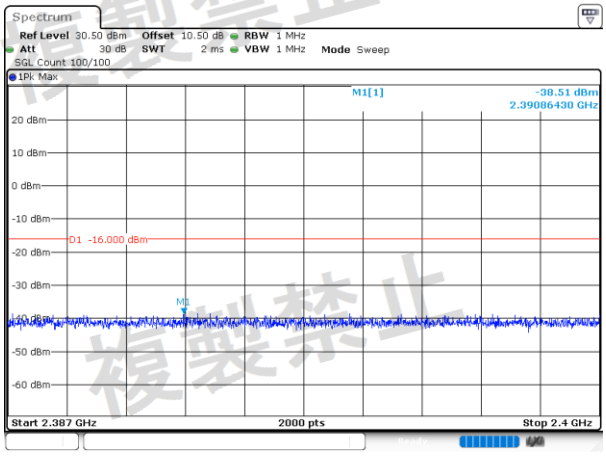
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:28:17

BLE 1M_High Channel(1GHz~2.387GHz)



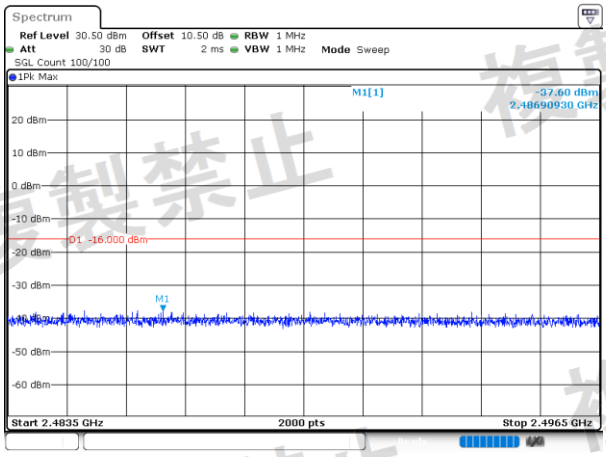
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:28:24

BLE 1M_High Channel(2.387GHz~2.4GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:28:30

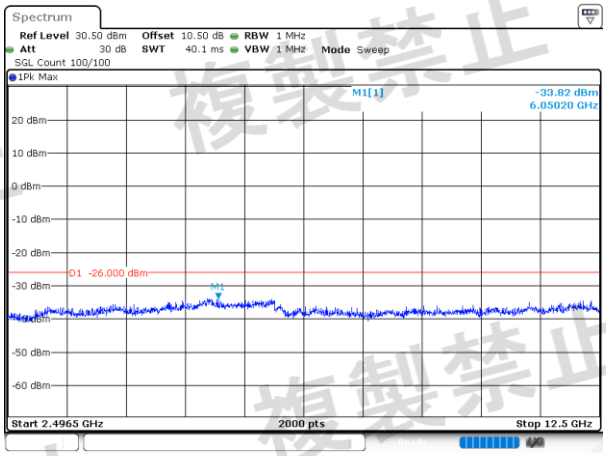
BLE 1M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:28:34

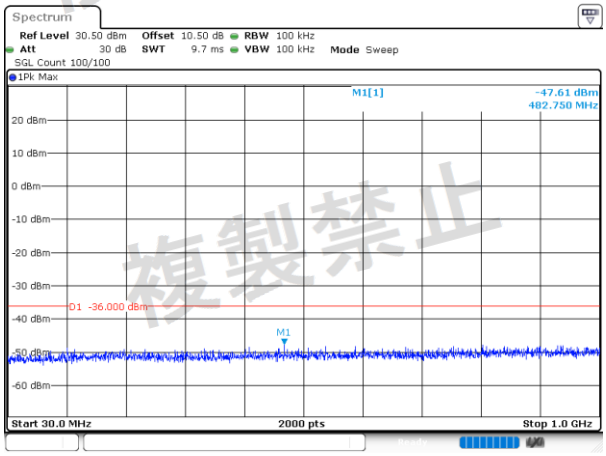
Test Condition: TC1

BLE 1M_High Channel(2.4965GHz~12.5GHz)



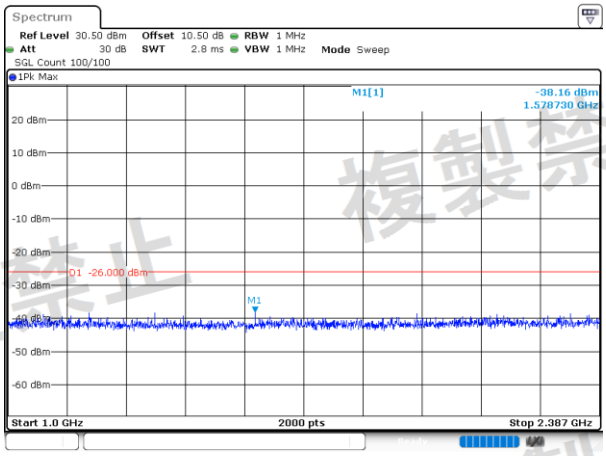
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:28:55

BLE 2M_Low Channel(30MHz~1GHz)



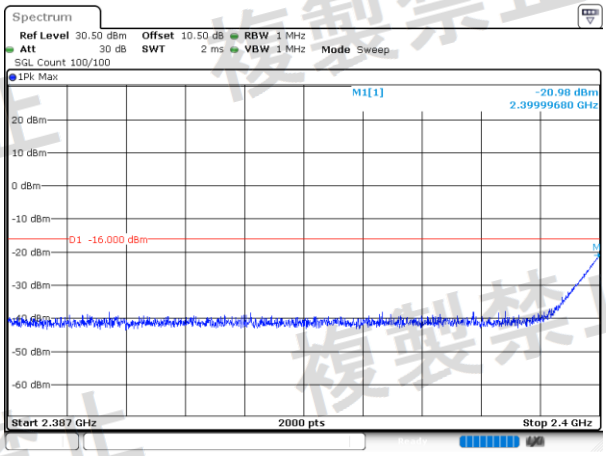
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:43:16

BLE 2M_Low Channel(1GHz~2.387GHz)



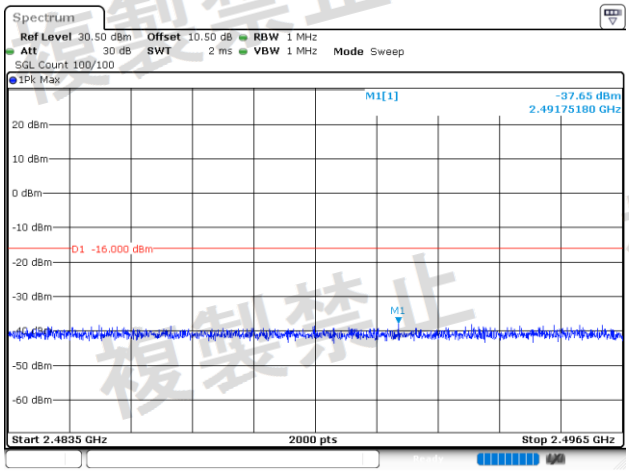
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:43:23

BLE 2M_Low Channel(2.387GHz~2.4GHz)



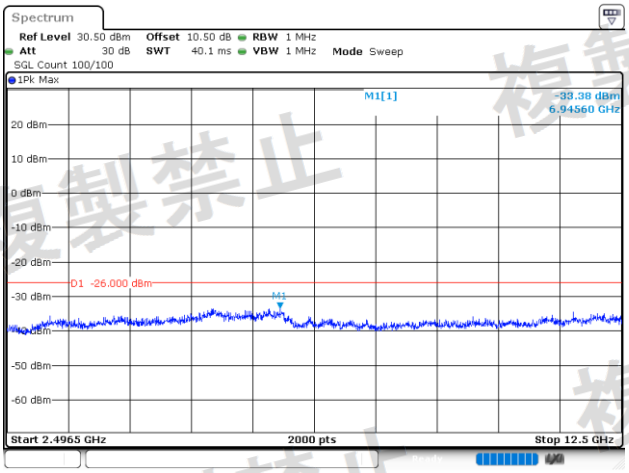
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:43:28

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



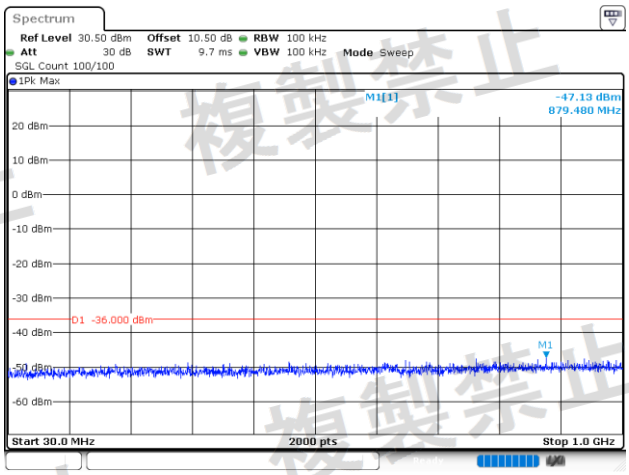
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:43:32

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



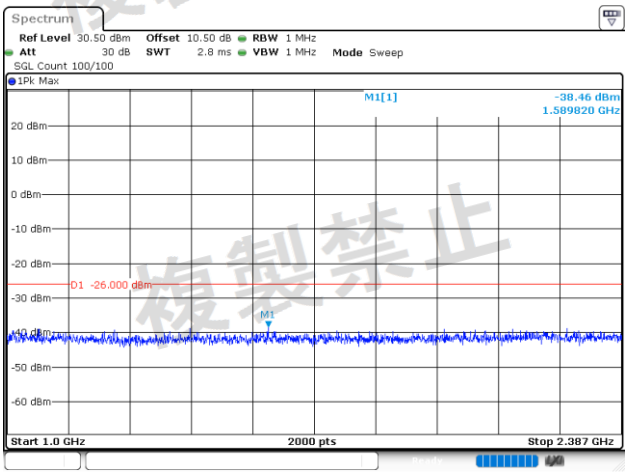
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:43:53

BLE 2M_Middle Channel(30MHz~1GHz)



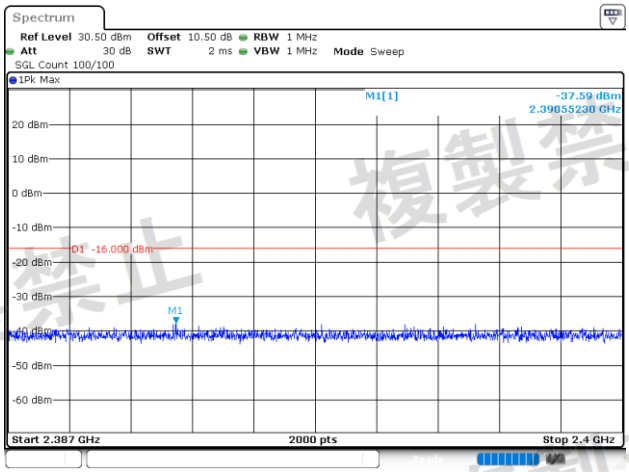
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:46:09

BLE 2M_Middle Channel(1GHz~2.387GHz)



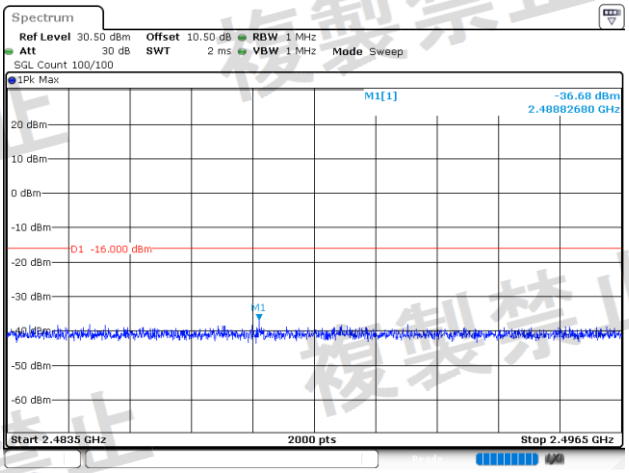
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:46:16

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



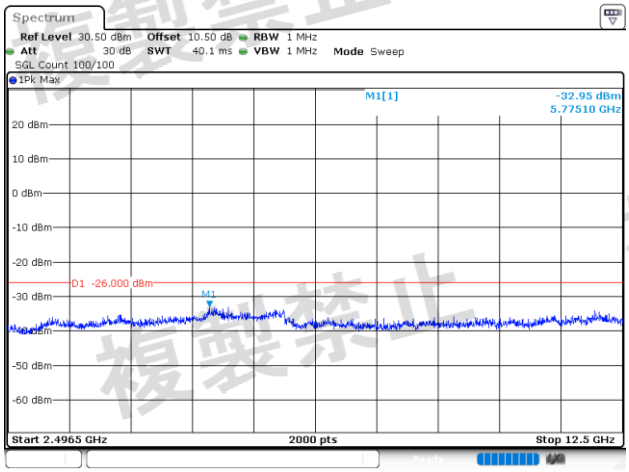
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:46:22

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



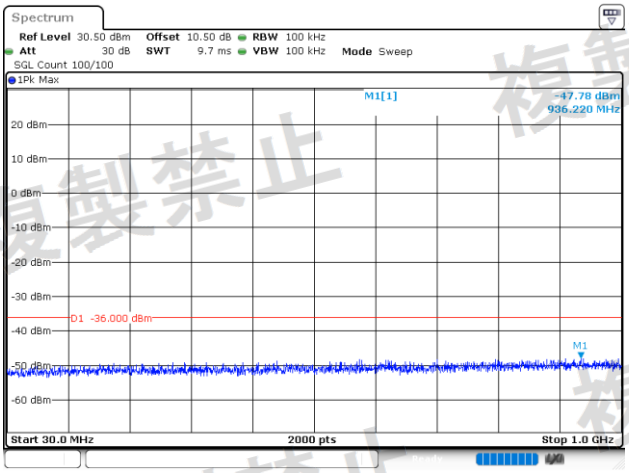
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:46:26

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



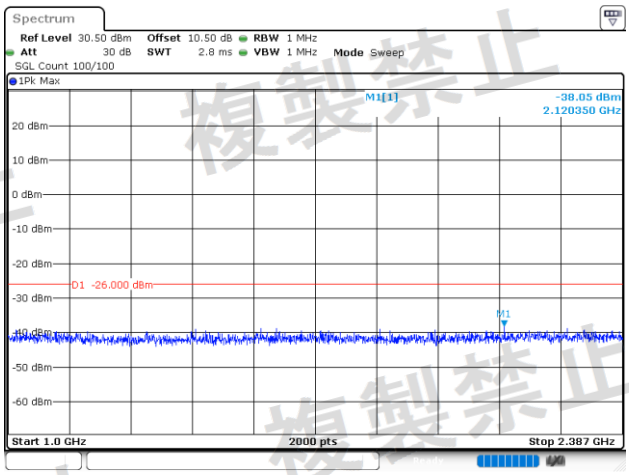
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:46:48

BLE 2M_High Channel(30MHz~1GHz)



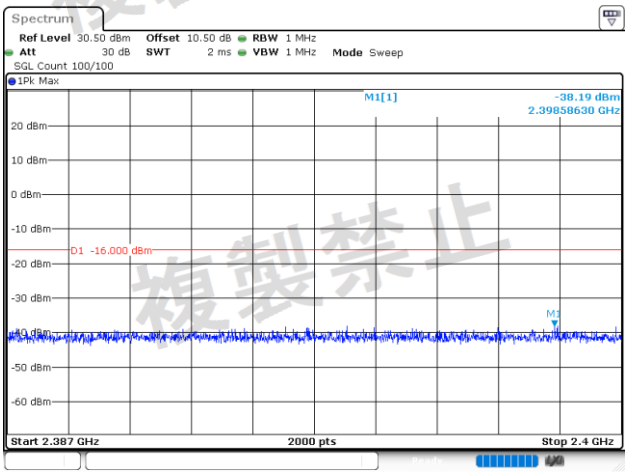
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:48:27

BLE 2M_High Channel(1GHz~2.387GHz)



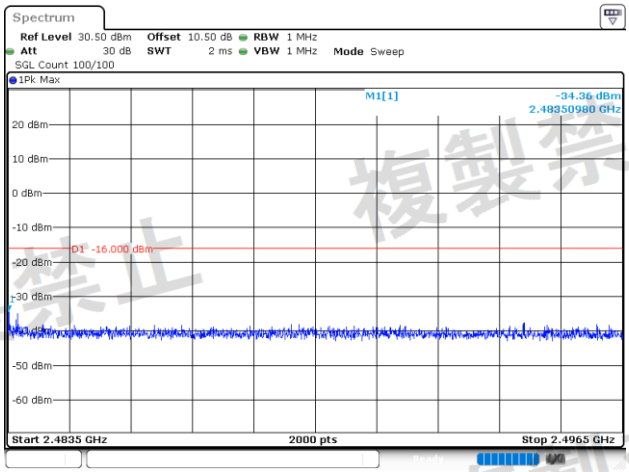
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:48:34

BLE 2M_High Channel(2.387GHz~2.4GHz)



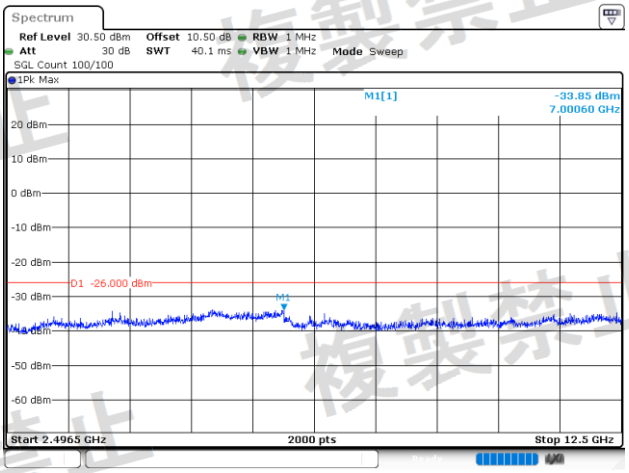
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:48:39

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:48:44

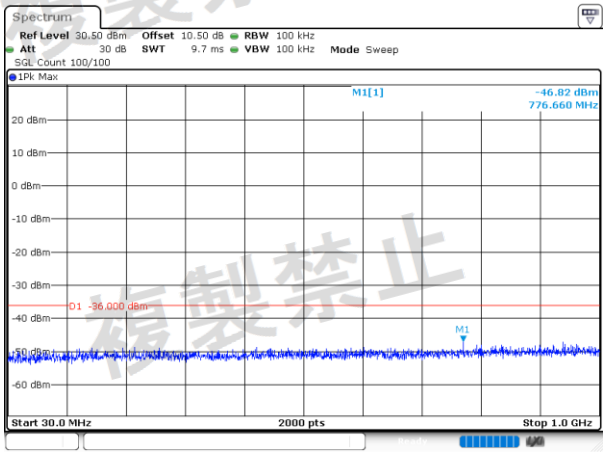
BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 09:49:06

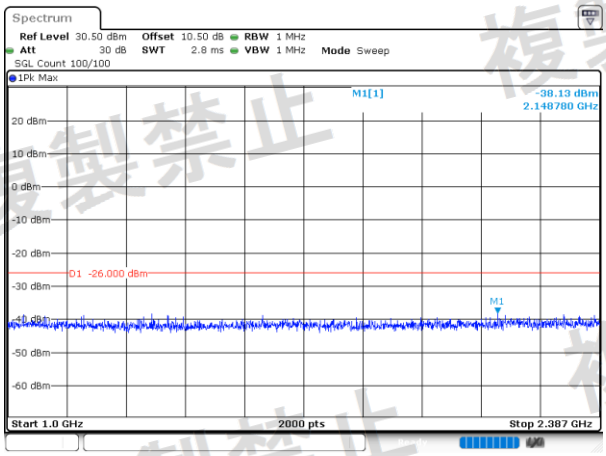
Test Condition: TC2

BLE 2M_Low Channel(30MHz~1GHz)



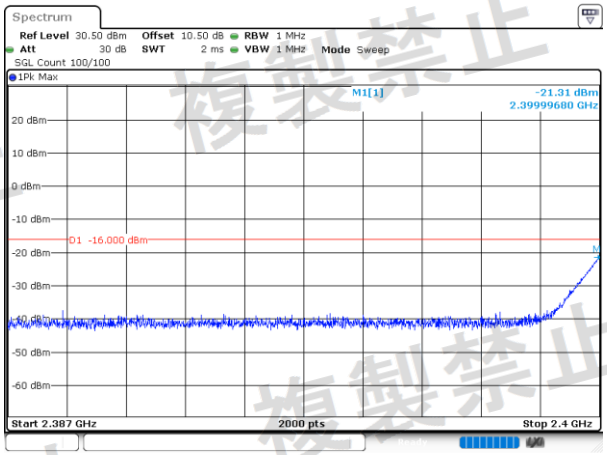
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:14:01

BLE 2M_Low Channel(1GHz~2.387GHz)



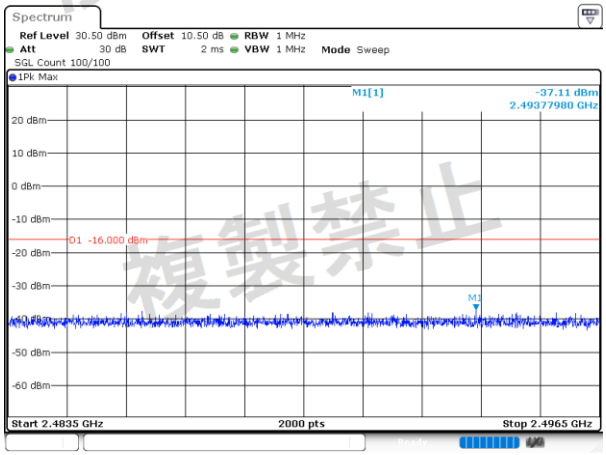
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:14:07

BLE 2M_Low Channel(2.387GHz~2.4GHz)



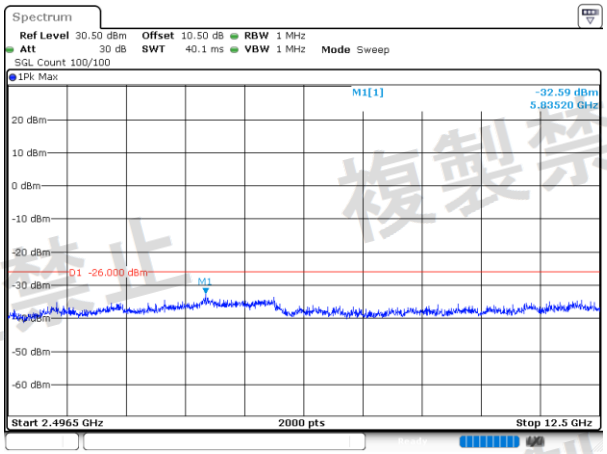
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:14:11

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



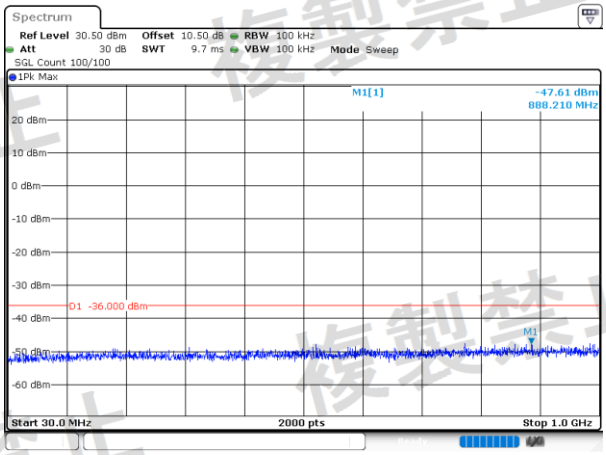
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:14:15

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



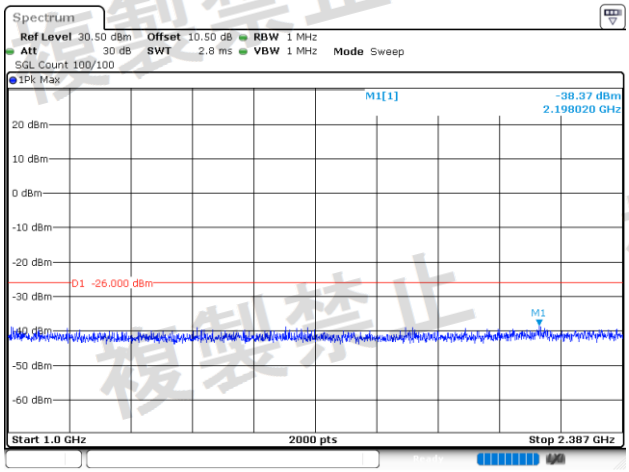
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:14:35

BLE 2M_Middle Channel(30MHz~1GHz)



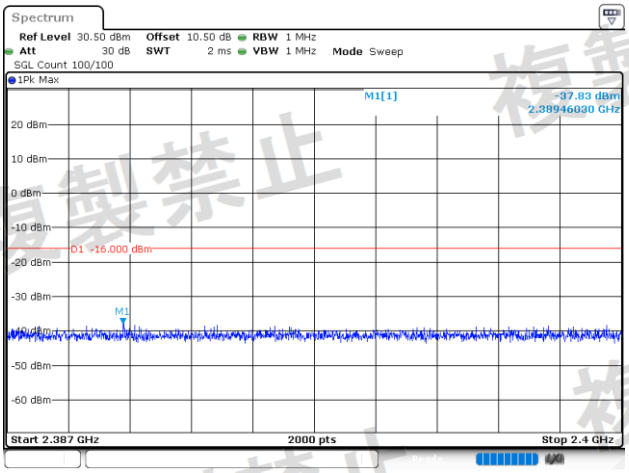
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:15:49

BLE 2M_Middle Channel(1GHz~2.387GHz)



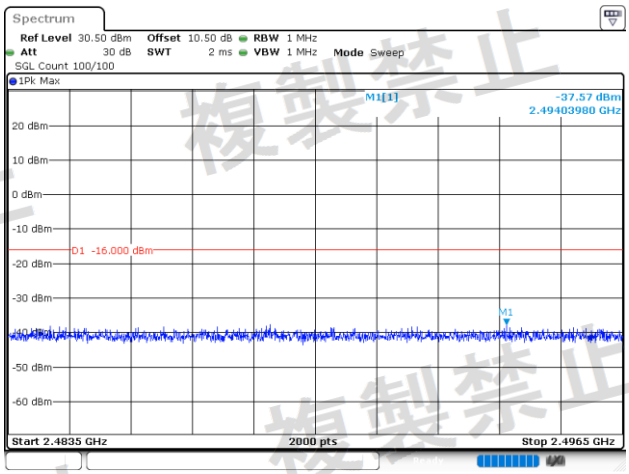
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:15:56

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



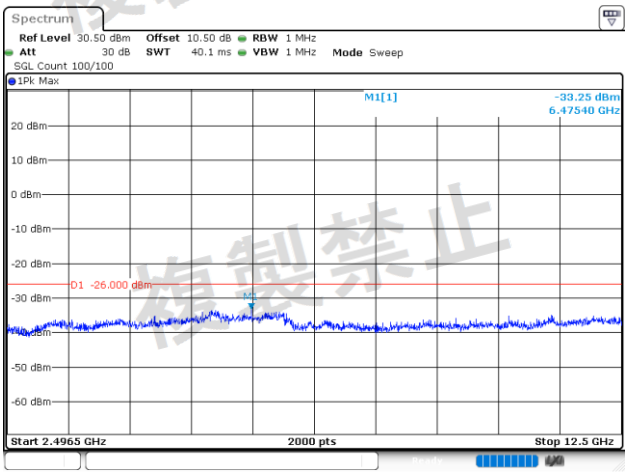
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:16:01

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



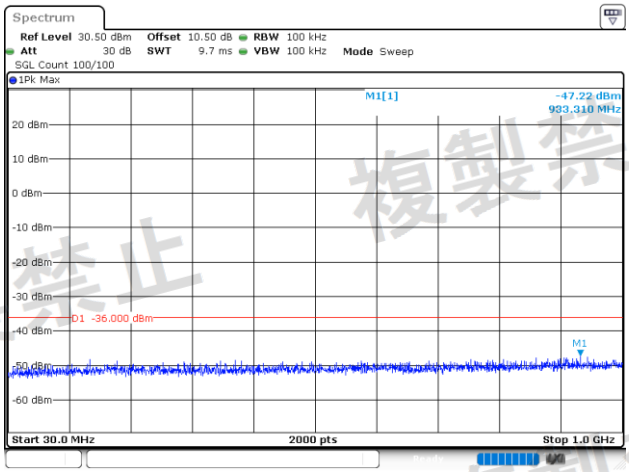
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:16:06

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



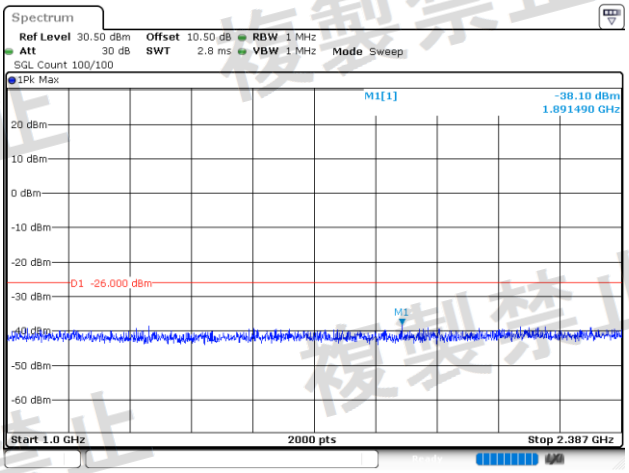
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:16:26

BLE 2M_High Channel(30MHz~1GHz)



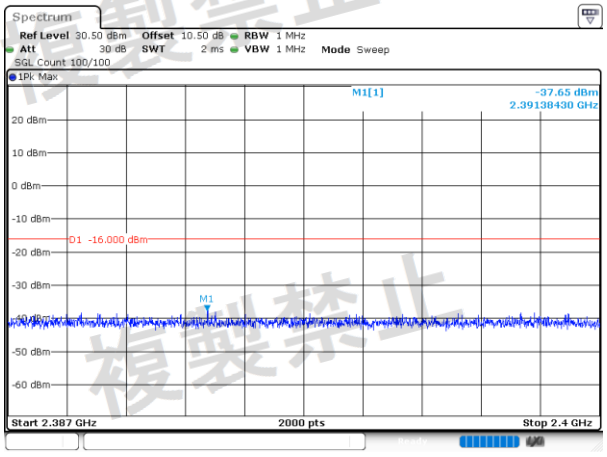
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:18:45

BLE 2M_High Channel(1GHz~2.387GHz)



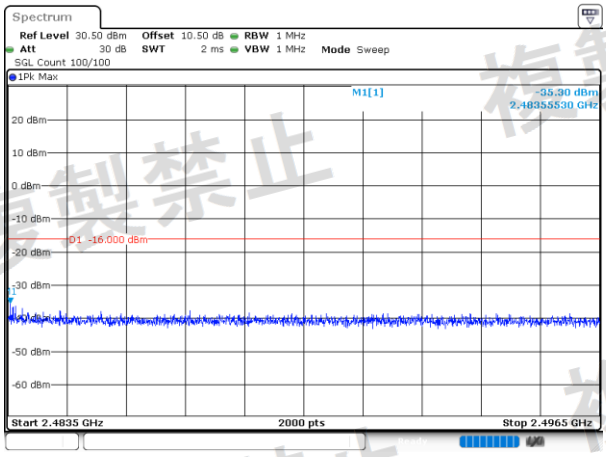
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:18:53

BLE 2M_High Channel(2.387GHz~2.4GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:18:58

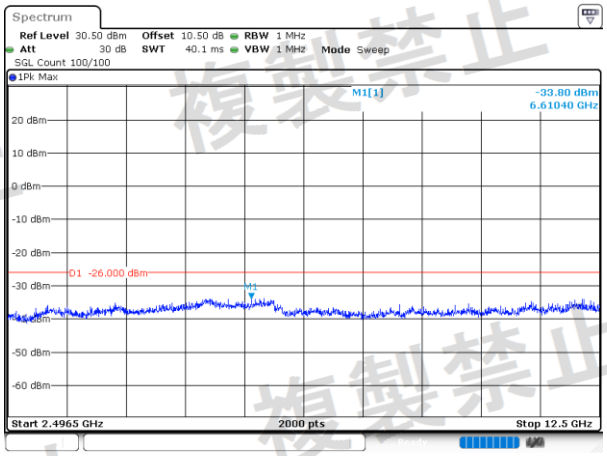
BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:19:02

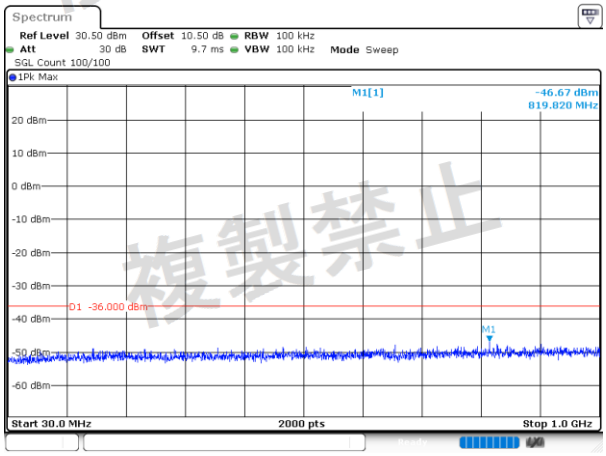
Test Condition: TC3

BLE 2M_High Channel(2.4965GHz~12.5GHz)



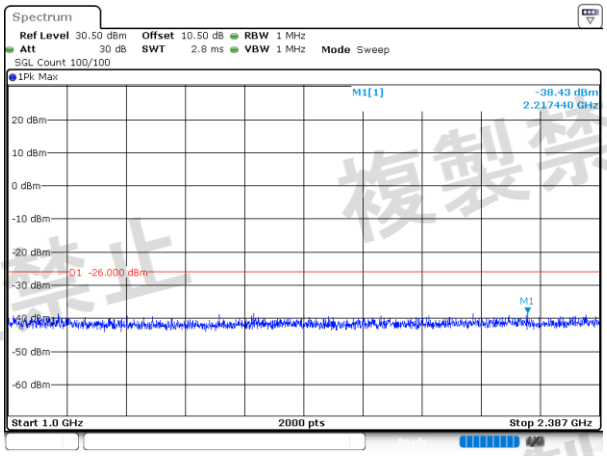
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:19:23

BLE 2M_Low Channel(30MHz~1GHz)



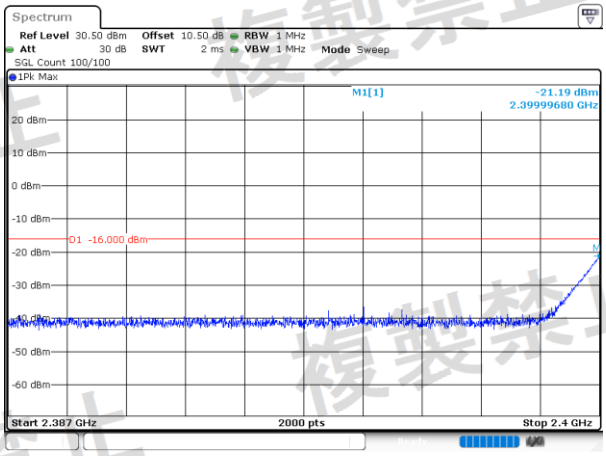
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:30:59

BLE 2M_Low Channel(1GHz~2.387GHz)



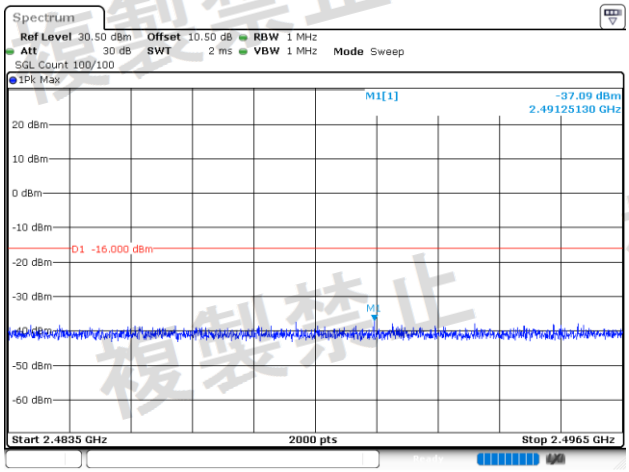
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:31:06

BLE 2M_Low Channel(2.387GHz~2.4GHz)



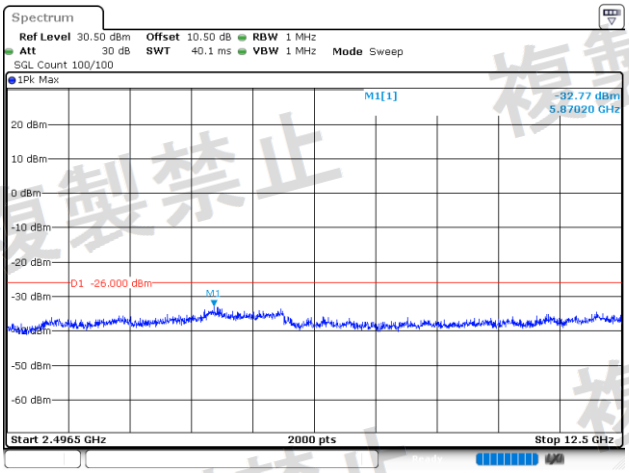
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:31:11

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



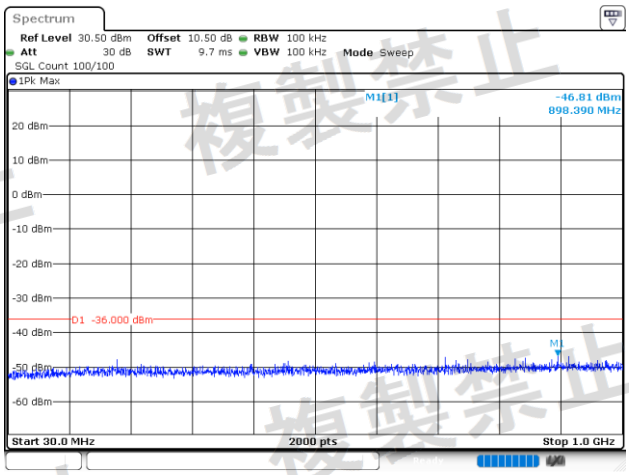
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:31:16

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



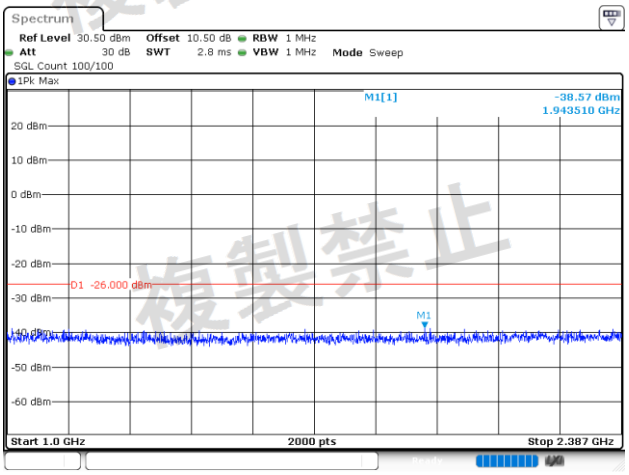
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:31:37

BLE 2M_Middle Channel(30MHz~1GHz)



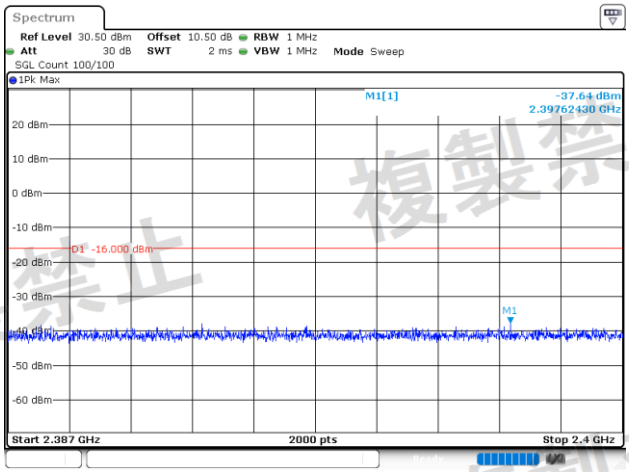
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:34:06

BLE 2M_Middle Channel(1GHz~2.387GHz)



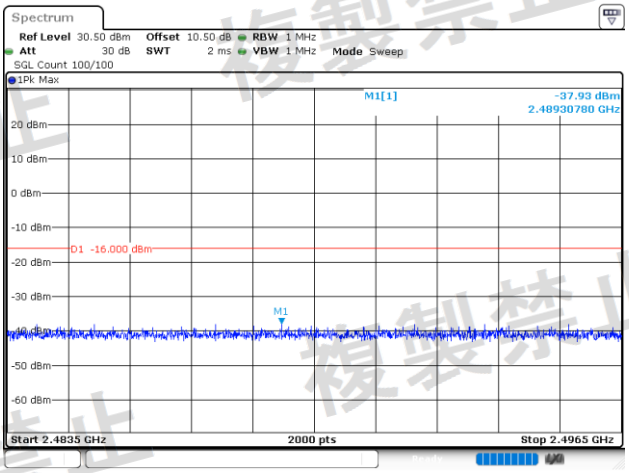
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:34:13

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



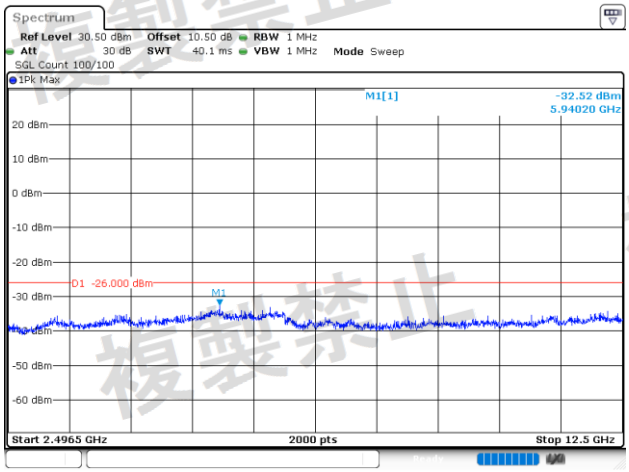
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:34:18

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



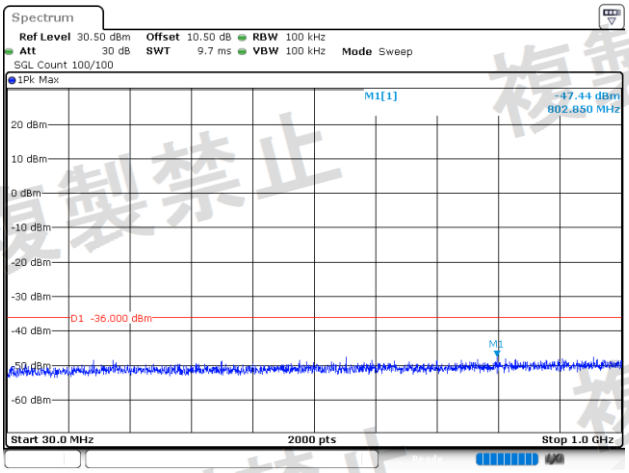
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:34:22

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



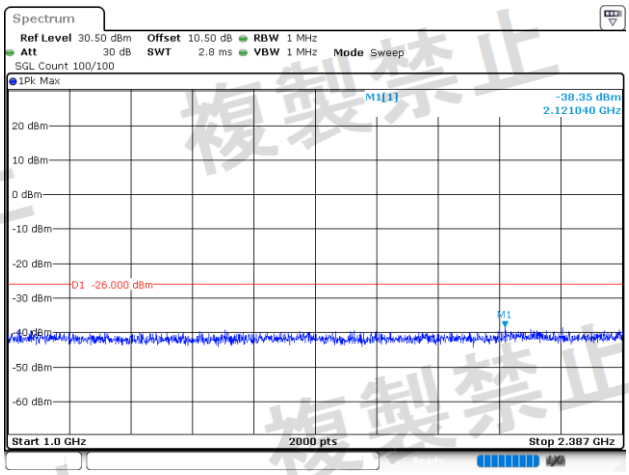
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:34:43

BLE 2M_High Channel(30MHz~1GHz)



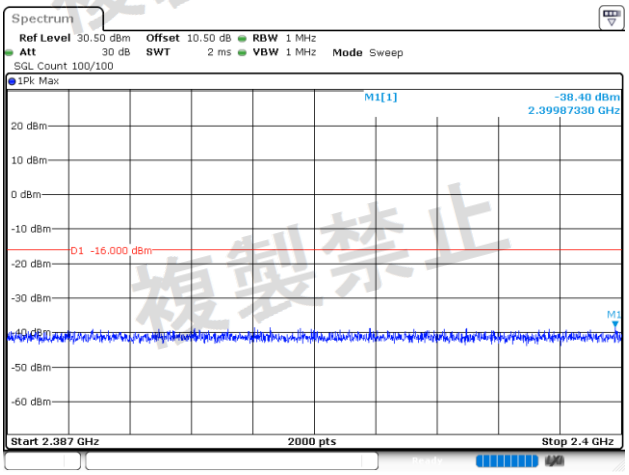
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:38:07

BLE 2M_High Channel(1GHz~2.387GHz)



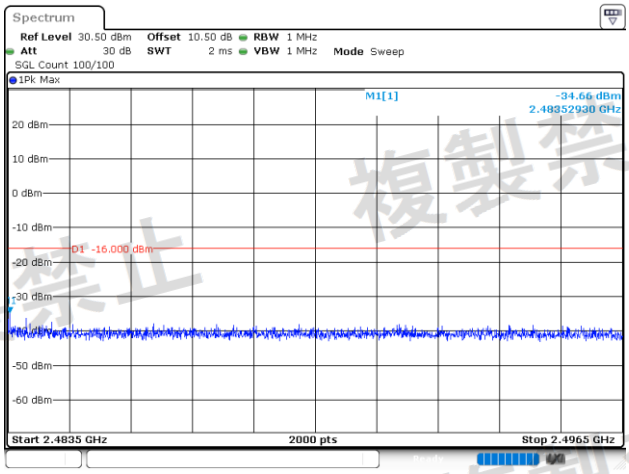
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:38:14

BLE 2M_High Channel(2.387GHz~2.4GHz)



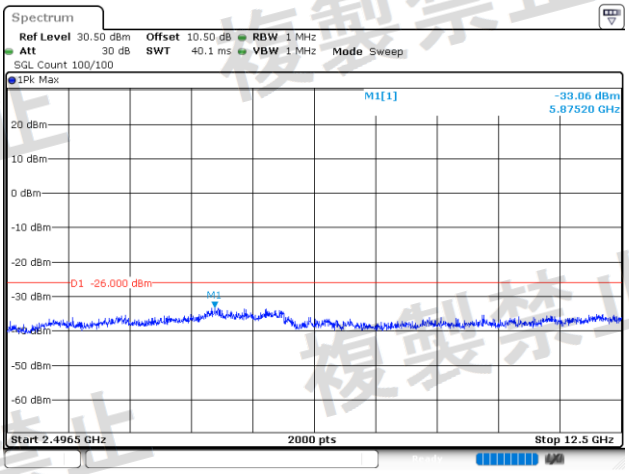
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:38:19

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:38:23

BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:38:44

Antenna Output Power and Output Power Tolerance

Test Condition: TC1

Mode	Antenna gain# (dBi)	Declared power# (mW)
BLE 1M	-6.11	3
BLE 2M		2

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	-0.39	0.914	≤ 10	-69.53	-80~+20	-6.50	≤ 12.14	Pass
	Middle	2.33	1.710		-43.00		-3.78		Pass
	High	4.48	2.805		-6.49		-1.63		Pass
BLE 2M	Low	-2.70	0.537	≤ 10	-73.15	-80~+20	-8.81	≤ 12.14	Pass
	Middle	0.03	1.007		-49.65		-6.08		Pass
	High	2.40	1.738		-13.11		-3.71		Pass

Test Condition: TC2

Mode	Antenna gain# (dBi)	Declared power# (mW)
BLE 1M	-6.11	3
BLE 2M		2

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	-0.02	0.995	≤ 10	-66.82	-80~+20	-6.13	≤ 12.14	Pass
	Middle	2.85	1.928		-35.75		-3.26		Pass
	High	5.22	3.327		10.89		-0.89		Pass
BLE 2M	Low	-2.49	0.564	≤ 10	-71.82	-80~+20	-8.60	≤ 12.14	Pass
	Middle	0.65	1.161		-41.93		-5.46		Pass
	High	3.22	2.099		4.95		-2.89		Pass

Test Condition: TC3

Mode	Antenna gain# (dBi)	Declared power# (mW)
BLE 1M	-6.11	3
BLE 2M		2

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	-0.54	0.883	≤ 10	-70.56	-80~+20	-6.65	≤ 12.14	Pass
	Middle	2.11	1.626		-45.82		-4.00		Pass
	High	5.08	3.221		7.37		-1.03		Pass
BLE 2M	Low	-2.42	0.573	≤ 10	-71.36	-80~+20	-8.53	≤ 12.14	Pass
	Middle	0.46	1.112		-44.41		-5.65		Pass
	High	2.59	1.816		-9.22		-3.52		Pass

Note:
Antenna otput power(mW) = 10^{Conducted power(dBm) / 10}
Antenna output power tolerance(%) = (Antenna output power - Declared power) / Declared power * 100%
Antenna output power(dBm) = 10 * log10{Antenna output power(mW)}
EIRP(dBm) = Antenna output power(dBm) + Antenna gain.

Receiver Spurious Emission and Unwanted Emission Intensity

Test Condition: TC1

Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	814.997	-67.06	0.197	4	Pass
		Band II (1MHz)	1000	12500	2430.31	-52.95	5.070	20	Pass
	Middle	Band I (100kHz)	30	1000	891.239	-67.86	0.164	4	Pass
		Band II (1MHz)	1000	12500	1782.86	-51.97	6.353	20	Pass
	High	Band I (100kHz)	30	1000	804.084	-67.44	0.180	4	Pass
		Band II (1MHz)	1000	12500	1767.91	-52.31	5.875	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	972.04	-67.04	0.198	4	Pass
		Band II (1MHz)	1000	12500	1782.86	-51.52	7.047	20	Pass
	Middle	Band I (100kHz)	30	1000	869.317	-67.35	0.184	4	Pass
		Band II (1MHz)	1000	12500	5880.31	-52.48	5.649	20	Pass
	High	Band I (100kHz)	30	1000	931.979	-67.70	0.170	4	Pass
		Band II (1MHz)	1000	12500	5883.76	-52.80	5.248	20	Pass

Test Condition: TC2

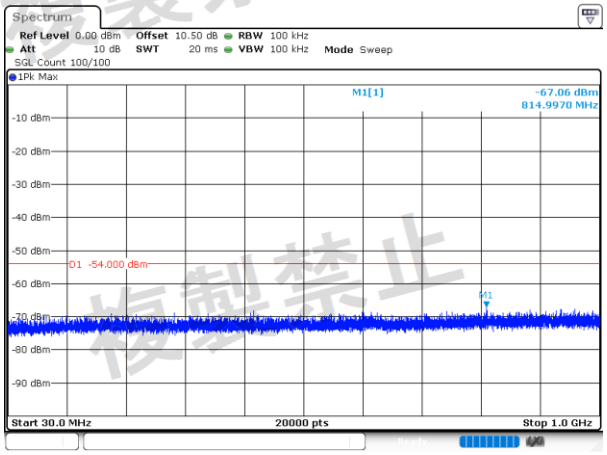
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	900.551	-67.48	0.179	4	Pass
		Band II (1MHz)	1000	12500	5838.91	-52.86	5.176	20	Pass
	Middle	Band I (100kHz)	30	1000	625.556	-67.97	0.160	4	Pass
		Band II (1MHz)	1000	12500	5922.29	-53.27	4.710	20	Pass
	High	Band I (100kHz)	30	1000	740.743	-67.49	0.178	4	Pass
		Band II (1MHz)	1000	12500	6274.19	-53.36	4.613	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	990.567	-67.59	0.174	4	Pass
		Band II (1MHz)	1000	12500	5851.56	-52.58	5.521	20	Pass
	Middle	Band I (100kHz)	30	1000	599.269	-66.92	0.203	4	Pass
		Band II (1MHz)	1000	12500	1772.51	-51.73	6.714	20	Pass
	High	Band I (100kHz)	30	1000	121.301	-66.88	0.205	4	Pass
		Band II (1MHz)	1000	12500	6952.69	-53.17	4.819	20	Pass

Test Condition: TC3

Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	891.433	-66.78	0.210	4	Pass
		Band II (1MHz)	1000	12500	6773.29	-53.38	4.592	20	Pass
	Middle	Band I (100kHz)	30	1000	909.669	-67.13	0.194	4	Pass
		Band II (1MHz)	1000	12500	6402.41	-53.08	4.920	20	Pass
	High	Band I (100kHz)	30	1000	850.402	-67.41	0.182	4	Pass
		Band II (1MHz)	1000	12500	5822.24	-52.81	5.236	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	987.366	-67.23	0.189	4	Pass
		Band II (1MHz)	1000	12500	6882.54	-53.21	4.775	20	Pass
	Middle	Band I (100kHz)	30	1000	882.848	-67.25	0.188	4	Pass
		Band II (1MHz)	1000	12500	6419.66	-53.31	4.667	20	Pass
	High	Band I (100kHz)	30	1000	764.12	-66.98	0.200	4	Pass
		Band II (1MHz)	1000	12500	12116.76	-53.24	4.742	20	Pass

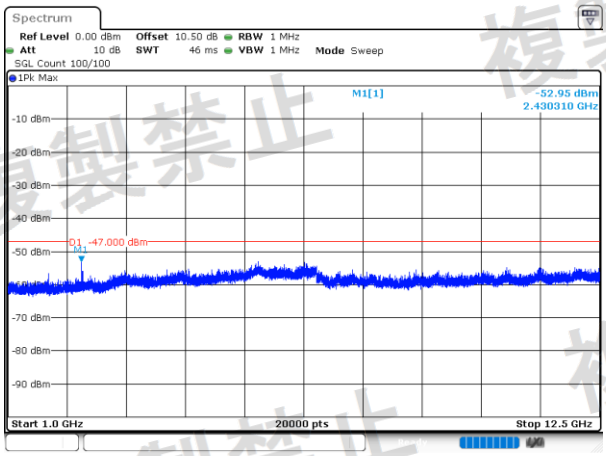
Test Condition: TC1

BLE 1M_Low Channel(30MHz~1GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:40:03

BLE 1M_Low Channel(1GHz~12.5GHz)



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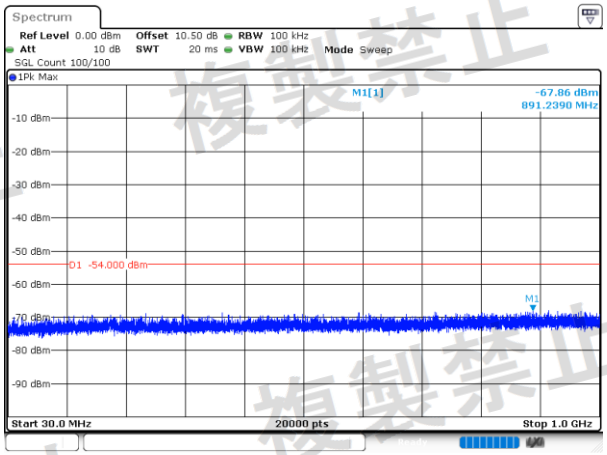
Date: 20.OCT.2025 10:40:27

BLE 1M_Middle Channel(30MHz~1GHz)



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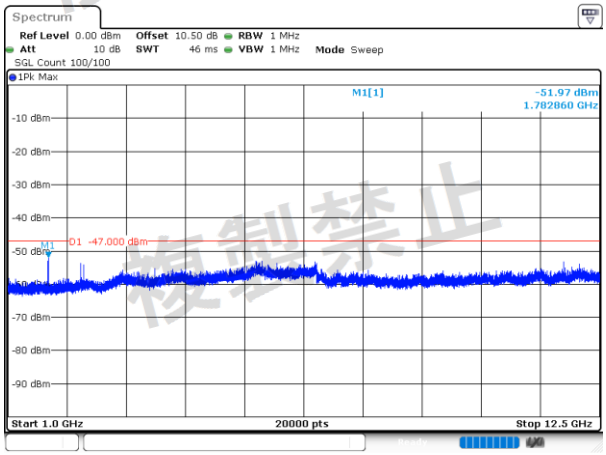
Date: 20.OCT.2025 10:40:46

BLE 1M_Middle Channel(1GHz~12.5GHz)



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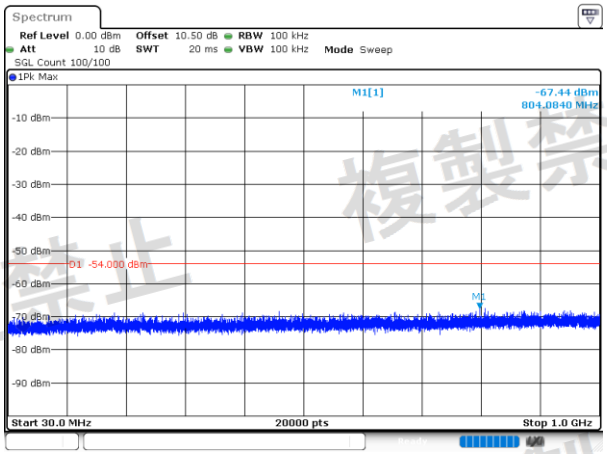
BLE 1M_High Channel(30MHz~1GHz)



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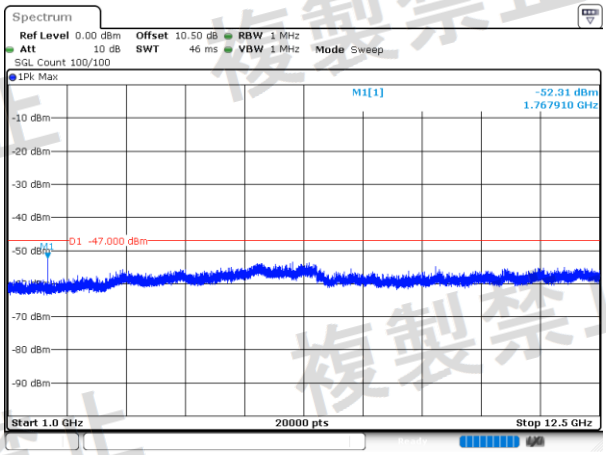
Date: 20.OCT.2025 10:41:52

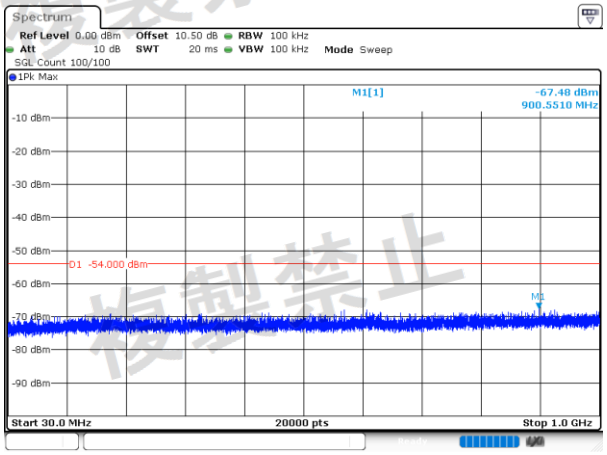
BLE 1M_High Channel(1GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:42:14

Test Condition: TC2

BLE 1M_Low Channel(30MHz~1GHz)



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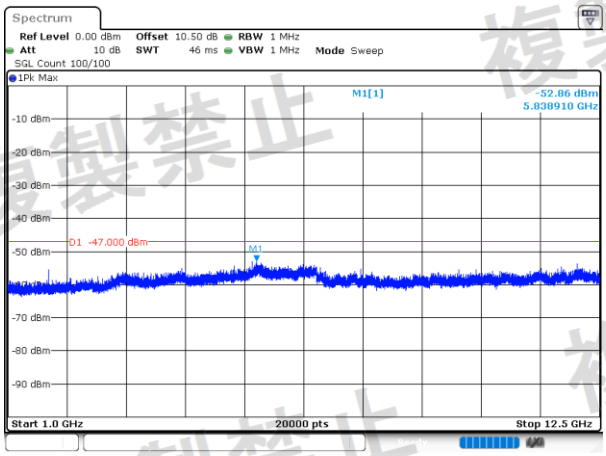
Date: 20.OCT.2025 10:44:31

BLE 1M_Low Channel(1GHz~12.5GHz)



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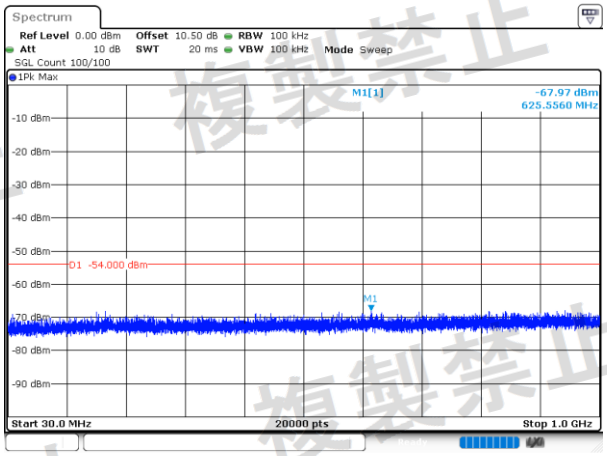
BLE 1M_Middle Channel(30MHz~1GHz)



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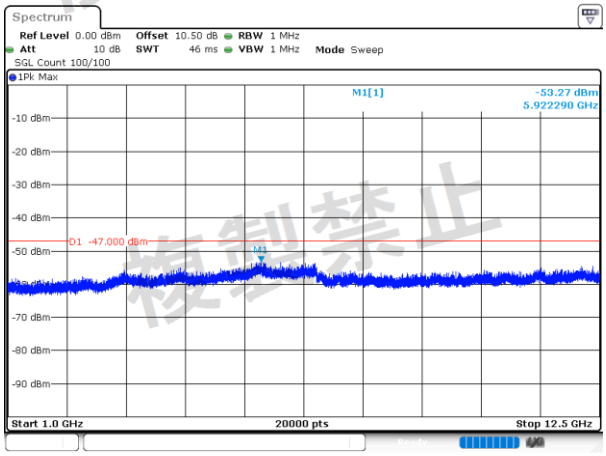
BLE 1M_Middle Channel(1GHz~12.5GHz)



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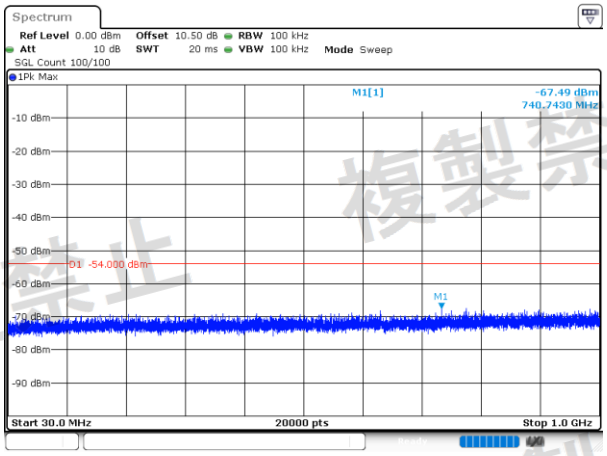
Date: 20.OCT.2025 10:45:34

BLE 1M_High Channel(30MHz~1GHz)



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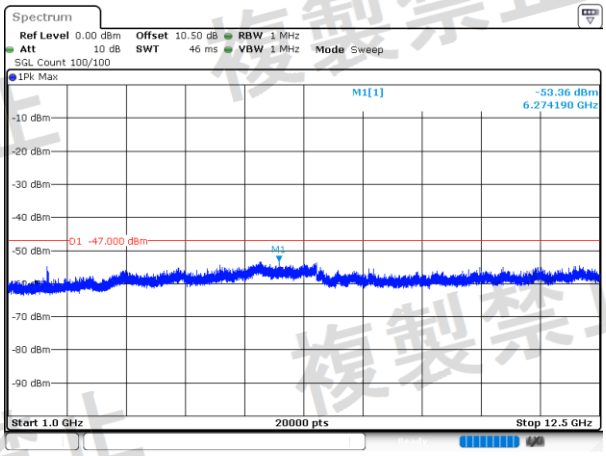
Date: 20.OCT.2025 10:45:52

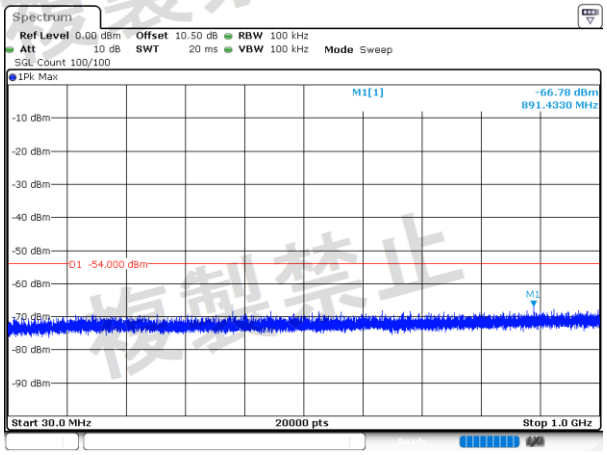
BLE 1M_High Channel(1GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:46:14

Test Condition: TC3

BLE 1M_Low Channel(30MHz~1GHz)



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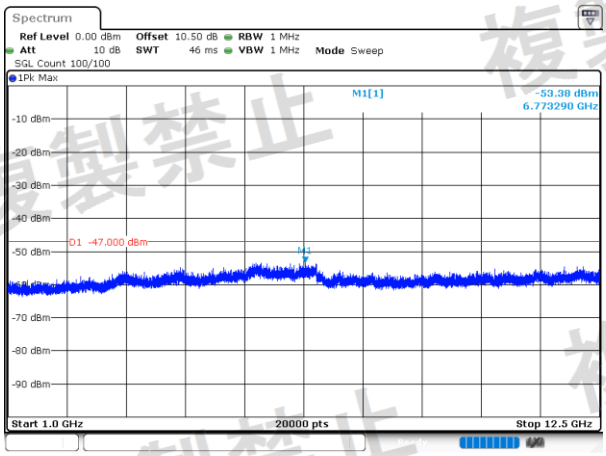
Date: 20.OCT.2025 10:49:50

BLE 1M_Low Channel(1GHz~12.5GHz)



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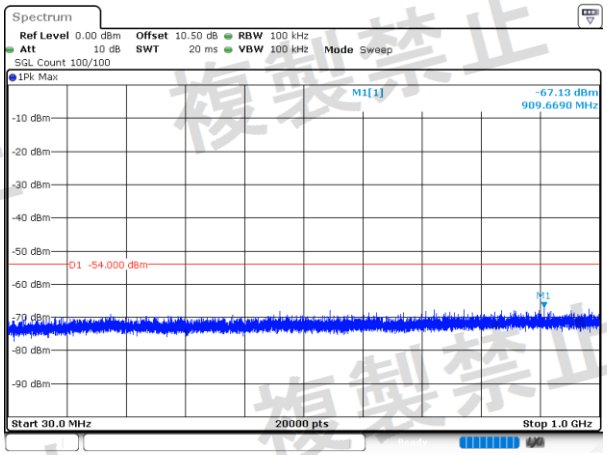
Date: 20.OCT.2025 10:50:12

BLE 1M_Middle Channel(30MHz~1GHz)



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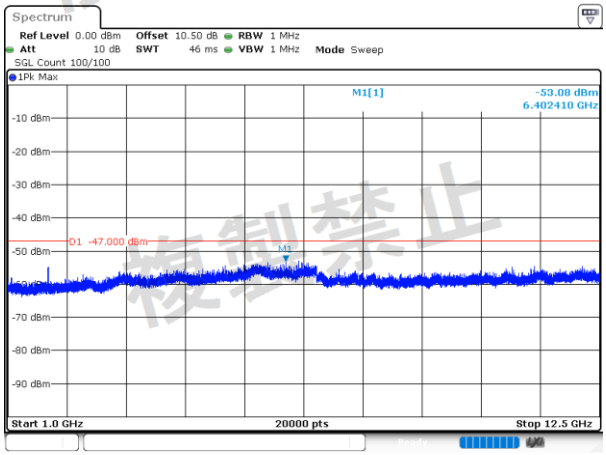
Date: 20.OCT.2025 10:50:41

BLE 1M_Middle Channel(1GHz~12.5GHz)



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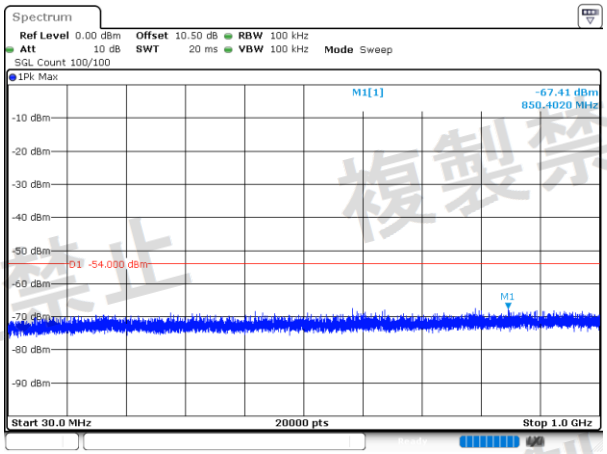
Date: 20.OCT.2025 10:51:03

BLE 1M_High Channel(30MHz~1GHz)



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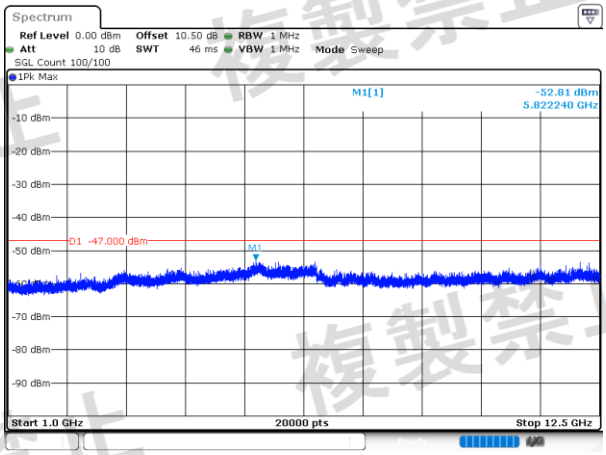
Date: 20.OCT.2025 10:52:36

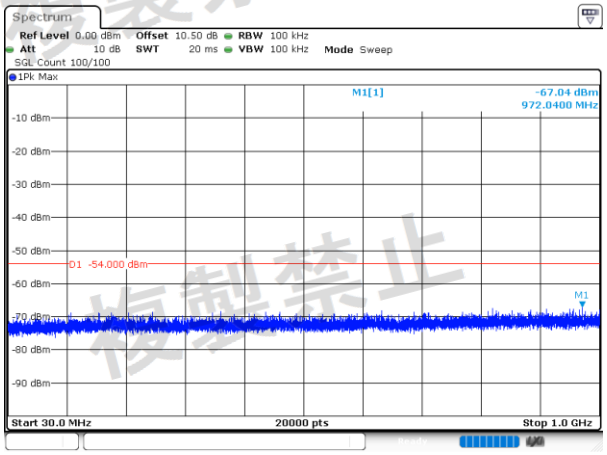
BLE 1M_High Channel(1GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:52:58

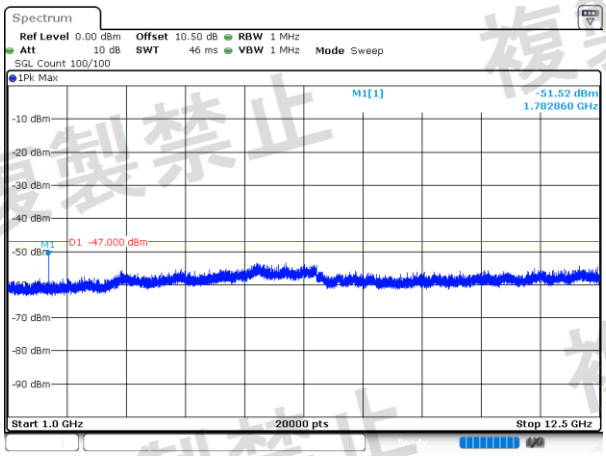
Test Condition: TC1

BLE 2M_Low Channel(30MHz~1GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:42:43

BLE 2M_Low Channel(1GHz~12.5GHz)



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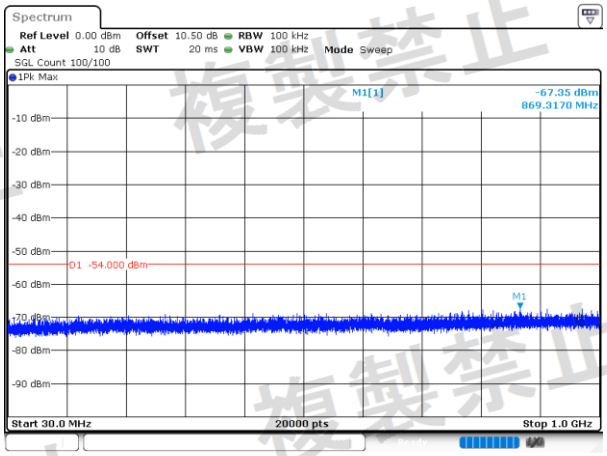
Date: 20.OCT.2025 10:43:05

BLE 2M_Middle Channel(30MHz~1GHz)



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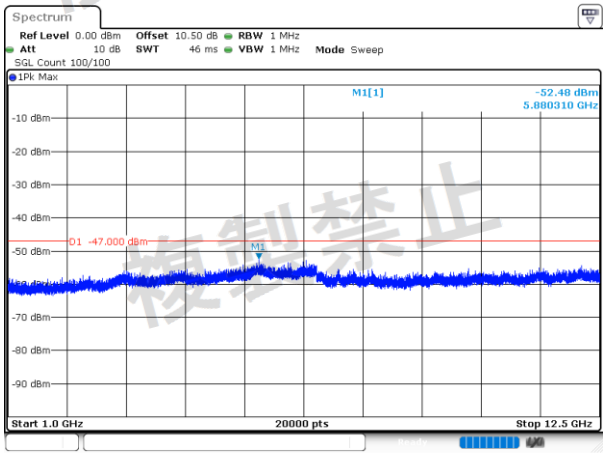
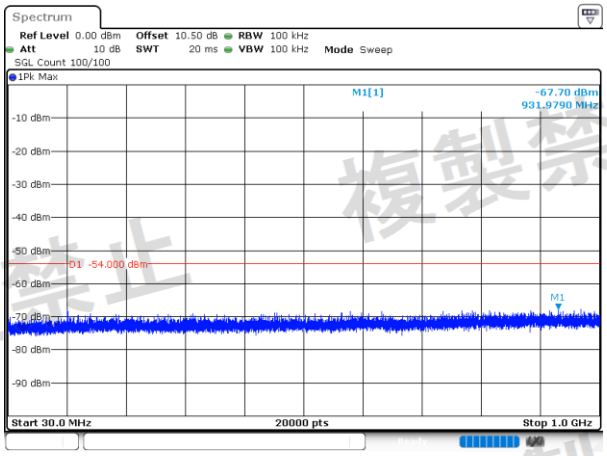
Date: 20.OCT.2025 10:43:18

BLE 2M_Middle Channel(1GHz~12.5GHz)



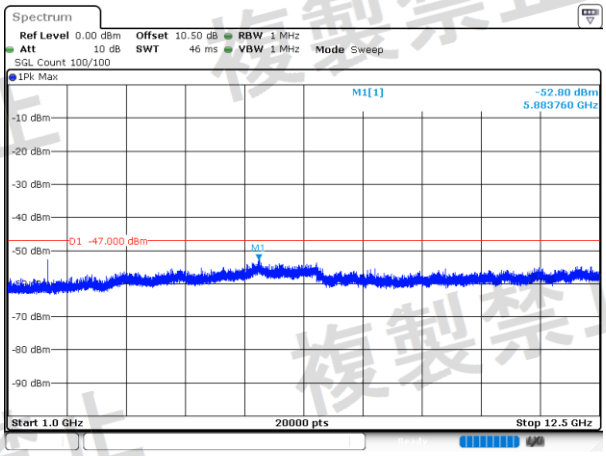
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:43:41

BLE 2M_High Channel(30MHz~1GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:43:53

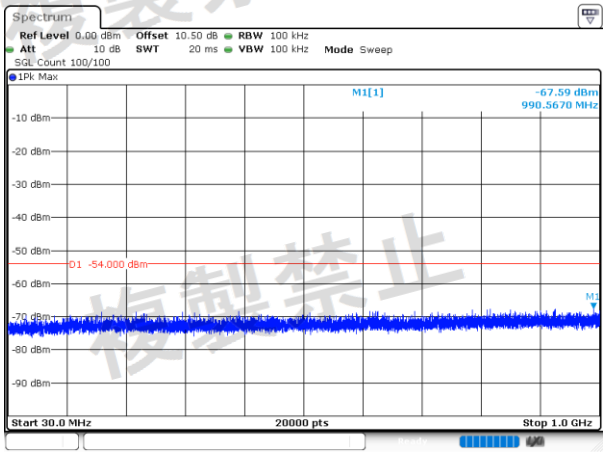
BLE 2M_High Channel(1GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:44:15

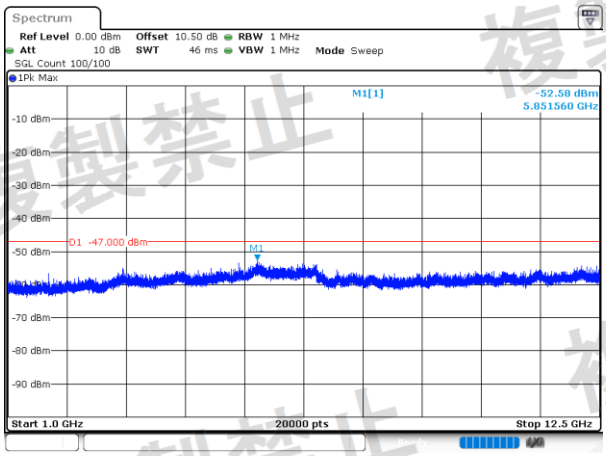
Test Condition: TC2

BLE 2M_Low Channel(30MHz~1GHz)



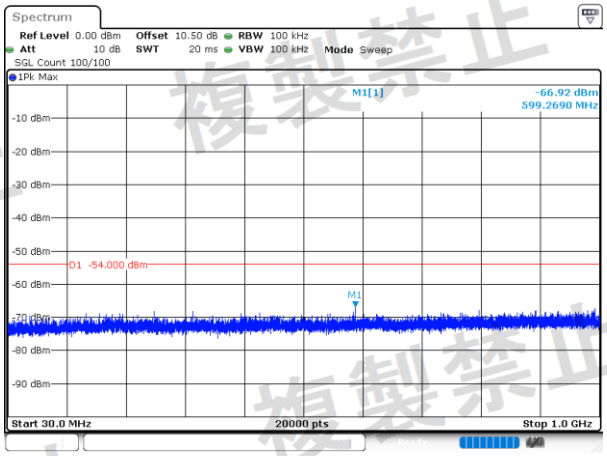
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:46:27

BLE 2M_Low Channel(1GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:46:48

BLE 2M_Middle Channel(30MHz~1GHz)



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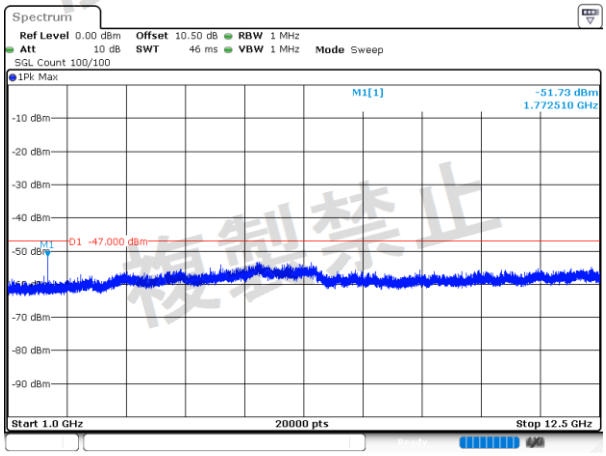
Date: 20.OCT.2025 10:48:29

BLE 2M_Middle Channel(1GHz~12.5GHz)



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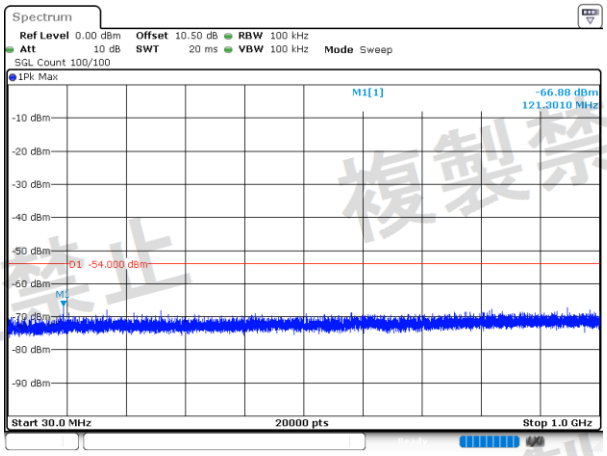
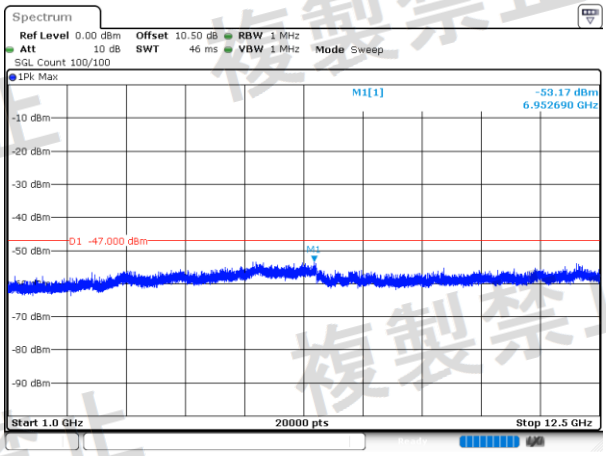
Date: 20.OCT.2025 10:48:51

BLE 2M_High Channel(30MHz~1GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:49:08

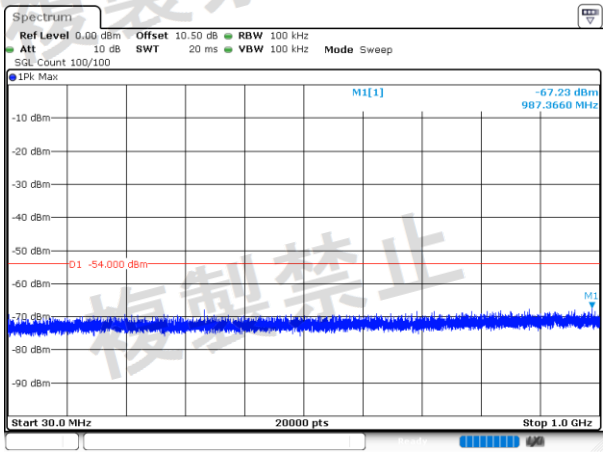
BLE 2M_High Channel(1GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:49:30

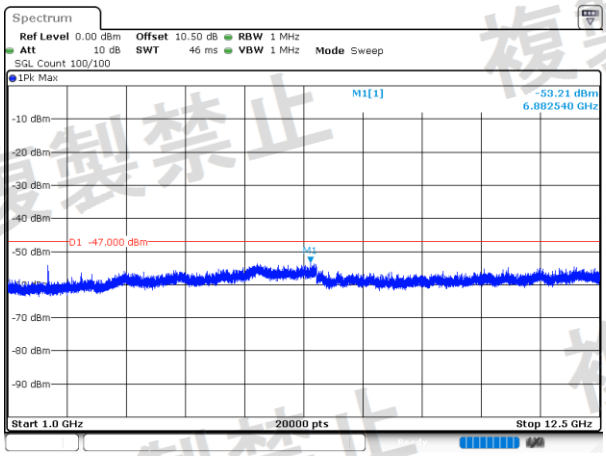
Test Condition: TC3

BLE 2M_Low Channel(30MHz~1GHz)



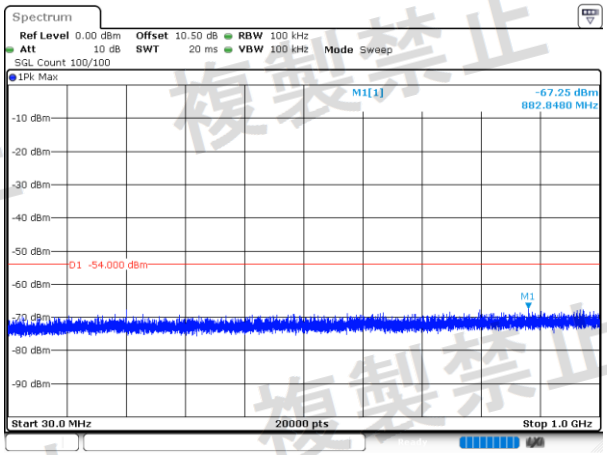
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:53:19

BLE 2M_Low Channel(1GHz~12.5GHz)



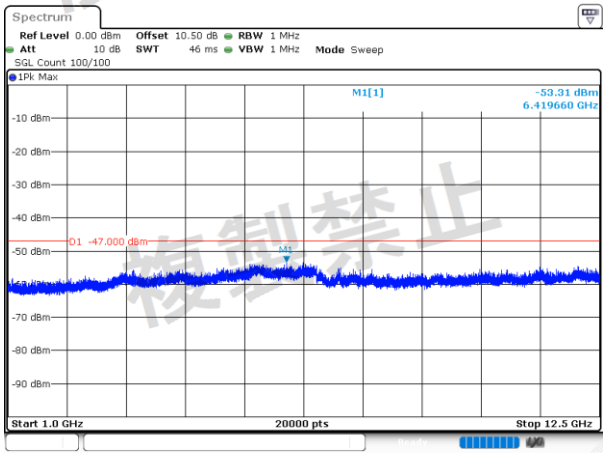
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:53:41

BLE 2M_Middle Channel(30MHz~1GHz)



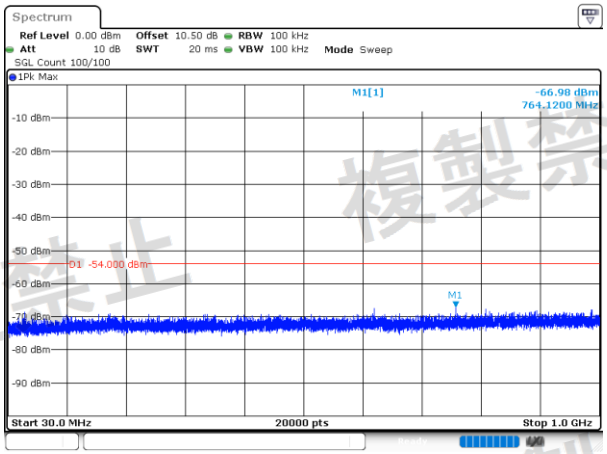
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:56:29

BLE 2M_Middle Channel(1GHz~12.5GHz)



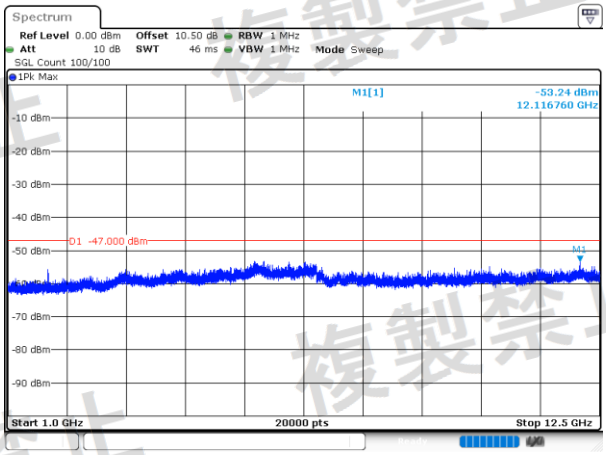
ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:56:51

BLE 2M_High Channel(30MHz~1GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:57:10

BLE 2M_High Channel(1GHz~12.5GHz)



ProjectNo.:2504X39110E-RF Tester:Cayde Hou
Date: 20.OCT.2025 10:57:32

Interference Prevention Function

Test Result: Good. MAC: 74:4D:BD:68:49:13

EXHIBIT A - EUT PHOTOGRAPHS

Please refer to the Attachment No.1 2504X39110E-RF EUT External Photos and Attachment No.2 2504X39110E-RF EUT Internal Photos.

EXHIBIT B - TEST SETUP PHOTOGRAPHS

Please refer to the Attachment No.3 2504X39110E-RF Test Photos.

******* END OF REPORT *******